ASMA Ver.	0. 7. 0 zvector- e7-0	6-Find (Zv	ector E7 V	RR-a in	structio	on)		12 Feb 2025 14: 26: 16 Page 3
LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
				108 *		Low co	ore PSWs	**********
00000000		00000000 00000000	00002B5F		VE7TST	START		Low core addressability
		00000140	00000000		SVOLDPSW	EQU	ZVE7TST+X' 140'	z/Arch Supervisor call old PSW
	00000001 80000000	00000000	000001A0	115 116		ORG DC	ZVE7TST+X' 1A0' X' 00000001800000	z/Architecure RESTART PSW
000001A8	00000000 00000200			117		DC	AD(BEGIN)	
	00020001 80000000 00000000 0000DEAD	000001B0	000001D0	119 120 121		ORG DC DC	ZVE7TST+X' 1D0' X' 000200018000000 AD(X' DEAD')	z/Archi tecure PROGRAM CHECK PSW 00'
000001E0		000001E0	00000200	123		ORG	ZVE7TST+X' 200'	Start of actual test program
				126 * 127 *	*****		The actual "ZVE	**************************************
				128 * 129 * 130 *	Archi t Regi st		e Mode: z/Arch age:	
				131 * 132 * 133 *	R0 R1-4	()	work) work)	
				134 * 135 * 136 *	R6- R7	' (ı	esting control tal work) irst base registe	ble - current test base r
				137 * 138 * 139 *	R9 R10	Se Tl	econd base registe hird base register 7TEST call return	er r
				140 * 141 * 142 *	R12 R13	E7 (v	7TESTS register work) ubroutine call	
				143 * 144 * 145 *	R15	Se	econdary Subrouti	ne call or work ***********************************
00000200 00000200 00000200		00000200 00001200 00002200		147 148 149		USING	BEGIN, R8 BEGIN+4096, R9 BEGIN+8192, R10	FIRST Base Register SECOND Base Register THIRD Base Register
00000200 00000202	0680			151 B 152	BEGI N	BALR BCTR	R8, 0 R8, 0	Initalize FIRST base register Initalize FIRST base register
	0680		00000	153		BCTR		Initalize FIRST base register
	4190 8800 4190 9800		00000800 00000800	155 156 157		LA LA	R9, 2048(, R8) R9, 2048(, R9)	Initalize SECOND base register Initalize SECOND base register

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LOC	OBJECT CODE	ADDR1	ADDR2	STM				
	41A0 9800 41A0 A800		00000800 00000800	159	LA LA	R10, 2048(, R9) R10, 2048(, R10)	Initalize THIRD base register Initalize THIRD base register	
00000216 0000021A	B600 8354 9604 8355		00000554 00000555	160 161 162	0I	RO, RO, CTLRO CTLRO+1, X' 04'	Store CRO to enable AFP Turn on AFP bit	
	9602 8355 B700 8354		00000555 00000554	163 164 165		CTLRO+1, X' 02' RO, RO, CTLRO	Turn on Vector bit Reload updated CRO	
				167 * Is z/A: 168 ******			**************************************	
00000226	47F0 80A8		000002A8		FCHECE B	K 129, 'z/Archi tect X0001	ture vector facility'	
0000022A 0000023E	40404040 E2928997 A961C199 838889A3			172+* 173+* 174+SKT0001	DC DC	C' Skipping to	Fcheck data area skip messgae ests: '	
	404D8289 A340F1F2	0000004E	0000001	175+ 176+ 177+SKL0001 178+*	DC DC EQU	C'z/Architecture C' (bit 129) is i *-SKT0001	not installed.'	
00000280	00000000 00000000 00000000 00000000 000000			179+ 179+ 180+FB0001 181+	DS DS DS	FD 4FD FD	facility bits gap	
		000002A8	00000001	182+* 183+X0001	EQU	*	gap	
000002B0	4100 0004 B2B0 8080 B982 0000		00000004 00000280	186+	XGR	RO, ((X0001-FB0002 FB0001 RO, RO	get facility bits	
	4300 8090 5400 8368 4770 80D0		00000290 00000568 000002D0	187+ 188+ 189+	I C N BNZ	RO, FB0001+16 RO, =F' 64' XC0001	get fbit byte is bit set?	
0000000	4400 0047			192+*		not set, issue m		
000002C4 000002C8	4100 004E 4110 802A 4520 8270		0000004E 0000022A 00000470	194+ 195+	LA LA BAL	RO, SKL0001 R1, SKT0001 R2, MSG	message length message address	
000002CC	47F0 8338	000002D0	00000538 00000001	196+ 197+XC0001	B EQU	E0J *		

		00000410	00000001	320 LAITCONI	LŲU		
00000418	5800 837	'4	00000574	321	L	R0, =F'1'	set failed test indicator
0000041C	5000 8E0	00		322 323	ST	RO, FAILED	
00000420	41C0 COC	4		324	LA	R12, 4(0, R12)	next test address
00000424	47F0 80I	14	000002D4	325	В	NEXTE7	
				327 ******	*****	*******	**********
				328 * end of 329 *******	testi:	ng; set ending psw **********	*********
		00000428		330 ENDTEST	EQU	*	
00000428	5810 8E0			331	L	R1, FAILED	did a test fail?
0000042C	1211			332	LTR	R1, R1	
0000042E	4780 833			333	BZ	E0J	No, exit
	AMEA OOF	· ^	00000550	334	В	FAI LTEST	Yes, exit with BAD PSW
00000432	47F0 835	OU	00000330	334	D	FAILIESI	ies, exit with DAD rsw

L_OC

000003B0

000003B4

000003B8

000003BE

000003C4

000003D0

000003D4

000003D8

000003DC

000003E2

000003E8

000003EE

000003F2

000003F6

000003FA

00000400

00000406

00000410

0000040C 4100 004D

00000414 45F0 8236

OBJECT CODE

4820 5004

4E20 8ED6

B982 0022

4320 5007

4E20 8ED6

B982 0022

4320 5008

4E20 8ED6

4110 8E08

000003CA D207 8E33 5015

D211 8ECO 8EAA

DE11 8ECO 8ED6

D202 8E18 8ECD

D211 8ECO 8EAA

DE11 8ECO 8ED6

D202 8E44 8ECD

D211 8ECO 8EAA

DE11 8ECO 8ED6

D202 8E51 8ECD

ADDR1

000003B0

000010C0

000010C0

00001018

00001033

000010C0

000010C0

00001044

000010C0

000010C0

00001051

ADDR2

0000001

00000004

000010D6

000010AA

000010D6

000010CD

00000015

0000007

000010D6

000010AA

000010D6

000010CD

00000008

000010D6

000010AA

000010D6

000010CD

0000004D

00001008

00000436

00000418 00000001

STM

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LOC	OBJECT CODE	ADDR1 ADDR2	STMI	•			

			337 338		RPTER		instruction test in error = MESSGAE LENGTH
			339				= MESSGAE LENGTH = ADDRESS OF MESSAGE
					*****		**********
00000436 0000043A	50F0 8254 5050 8258	000004 000004	58 34 3		ST ST	R15, RPTSAVE R5, RPTSVR5	Save return address Save R5
			344 345 346	*	Use H	ercules Diagnose for	Message to console
0000043E	9002 8260	000004			STM	RO, R2, RPTDWSAV	save regs used by MSG
00000442	4520 8270	000004	70 348		BAL	R2, MSG	call Hercules console MSG display
00000446	9802 8260	000004	60 349		LM	RO, R2, RPTDWSAV	restore regs
0000044A	5850 8258	000004	58 351		L	R5, RPTSVR5	Restore R5
0000044A	58F0 8254	00004			L	R15, RPTSAVE	Restore return address
00000452	07FF	-	353		BR	R15	Return to caller
00000454	00000000		355	RPTSAVE	DC	F' 0'	R15 save area
00000458	00000000				DC	F' 0'	R5 save area
00000460	00000000 00000000		358	RPTDWSAV	DC	2D' 0'	RO-R2 save area for MSG call
			361 362	*	Issue	HERCULES MESSAGE po R2 = return address	**************************************
00000470	4000 0000	00000					
00000470 00000474	4900 8378	000005	/8 365 366	MSG	CH BNHR	RO, =H' O'	Do we even HAVE a message? No, ignore
70000474	0702		300		DNIII	Rω	no, Ignore
00000476	9002 82AC	000004	AC 368		STM	RO, R2, MSGSAVE	Save registers
000047A	4900 837A	000005	7A 370		СН	RO, =AL2(L' MSGMSG)	Message length within limits?
0000047E	47D0 8286	000004			BNH	MSGOK	Yes, continue
00000482	4100 005F	000000	5F 372		LA	RO, L' MSGMSG	No, set to maximum
00000486	1820			MSGOK	LR	R2, R0	Copy length to work register
00000488 0000048A	0620 4420 82B8	000004	375 B8 376		BCTR EX	R2, 0 R2, MSGMVC	Minus-1 for execute Copy message to O/P buffer
0000048E 00000492	4120 200A 4110 82BE	000000 000004			LA LA	R2, 1+L' MSGCMD(, R2) R1, MSGCMD	Calculate true command length Point to true command
00000496 0000049A	83120008 4780 82A6	000004	381 46 382 383		DC BZ	X' 83' , X' 12' , X' 0008' MSGRET	Issue Hercules Diagnose X'008' Return if successful
0000049E 000004A0	1222 4780 82A6	000004	384		LTR BZ	R2, R2 MSGRET	Is Diag8 Ry (R2) 0? an error occurred but coninue
00004A4	0000		387		DC	Н' О'	CRASH for debugging purposes
00004A6	9802 82AC	000004	AC 389	MSGRET	LM	RO, R2, MSGSAVE	Restore registers
							<u> </u>

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LOC	OBJECT CODE	ADDR1	ADDR2	STMI			
000004AA	07F2			390	BR	R2	Return to caller
	00000000 00000000			392 MSGSAVE	DC	3F' 0'	Registers save area Executed instruction
000004B8	D200 82C7 1000	000004C7	00000000	393 MSGMVC	MVC	MSGMSG(0), 0(R1)	Executed instruction
000004BE 000004C7	D4E2C7D5 D6C8405C 40404040 40404040			395 MSGCMD 396 MSGMSG 397	DC DC	C' MSGNOH * ' CL95' '	*** HERCULES MESSAGE COMMAND *** The message text to be displayed

ASMA Ver.	0. 7. 0 zvector-e7-0	6-Find (Zv	ector E7 VI	RR-ai	nstructi	on)		12 Feb 2025	14: 26: 16	Page	10
LOC	OBJECT CODE	ADDR1	ADDR2	STMT							
				399 400 401	****** * ******	****** Norma *****	**************************************	**************************************	************	****	
00000528	00020001 80000000			403	E0JPSW	DC	0D' 0' , X' 000200018000000	0', AD(0)			
00000538	B2B2 8328		00000528	405	E0J	LPSWE	E0JPSW	Normal completion			
00000540	00020001 80000000			407	FAI LPSW	DC	0D' 0' , X' 000200018000000	0', AD(X'BAD')			
00000550	B2B2 8340		00000540	409	FAI LTEST	LPSWE	FAILPSW	Abnormal terminat	i on		
				411 412 413	****** * ******	****** Worki 1 *****	**************************************	*******************	******* *****	****	
	00000000 00000000			415 416	CTLRO	DS DS	F F	CRO			
	00000000 00000001 00000040			418 419 420		LTORG	, =D' 1' =F' 64'	Literals pool			
00000570 00000574				421 422 423			=A(E7TESTS) =XL4'3' =F'1'				
00000578 0000057A	0000 005F			424 425 426			=H' 0' =AL2(L' MSGMSG)				
				427 428		some	constants				
		00000400 00001000 00010000 00100000	00000001 00000001 00000001	431 432	PAGE K64	EQU EQU EQU	1024 (4*K) (64*K) (K*K)	One KB Size of one page 64 KB 1 MB			
		AABBCCDD 000000DD	00000001 00000001		REG2PATT REG2LOW		X' AABBCCDD' X' DD'	Polluted Register (last byte above)	pattern		

ASMA Ver.	0. 7. 0 zvector- e7- 0	6-Find (Zve	ctor E7 V	VRR-a	nstructi	on)		12 Feb 2025	14: 26: 16	Page	12
LOC	OBJECT CODE	ADDR1	ADDR2	STMI							
				191	******	*****	******	*******	******	****	
				485	*	TEST :		ing storge *********			
00001014	40010000 0000000				*****					****	
000010AA	40212020 20202020			487 488	EDIT	DC	XL18 402120202020202	020202020202020202020'			
000010BC	7E7E7E6E			489		DC	C' ===>'				
	40404040 40404040 4C7E7E7E			490 491	PRT3	DC DC	CL18' ' C' <==='				
	00000000 00000000				DECNUM	DS	CL16				
				494	*****	*****	*******	********	******	****	
				495	*	Vecto	r instruction results	, pollution and input		ale ale ale ale	
000010E8				496 497	****	DS	0F	*******	* * * * * * * * * *	****	
000010E8	00000000 00000000			498		DS	XL16		gap V1 FUDGE		
000010F8 00001108	FFFFFFF FFFFFFF 00000000 00000000			499 500	V1FUDGE	DC DS	XL16' FFFFFFFFFFFFF XL16	FFFFFFFFFFFFFF	V1 FUDGE		
00001108				300		אט	AL10				
				502	*****	*****	*******	********	******	****	
				503	*	E7TES	Γ DSECT				
				504	*****	*****	******	*******	******	****	
00000000	00000000				E7TEST TSUB	DSECT DC	, A(0)	pointer to test			
	0000000				TNUM	DC	H' 00'	Test Number			
	00			509	M	DC	X' 00'	MD mond			
00000007 00000008	00 00			510 511		DC DC	HL1' 00' HL1' 00'	MB used M5 used			
00000009	00			512	CC	DC	HL1' 00'	cc expected			
000000A	00			513 514	CCMASK *	DC	HL1' 00'	not expected CC m	ask		
				515	*	CC ex	trtaction				
0000000	0000000 00000000			516 517	* CCPSW	DS	2F	extract PSW after	tost (has	CC)	
00000000						DS DS	X	extract rsw after extracted cc	test (lias		
				519							
	40404040 40404040 00000000				OPNAME V1ADDR	DC DC	CL8' ' A(0)	E7 name address of v1 resu	ıl t		
00000024	0000000			522	V2ADDR	DC	A(0)	address of v2 sour	rce		
	00000000				V3ADDR RELEN	DC DC	A(0)	address of v3 sour RESULT LENGTH	rce		
0000002C 00000030						DC DC	A(0) A(0)	result (expected)	address		
0000038	0000000 00000000			526		DS	FD	gap V1 Output			
	00000000 00000000 00000000 00000000			527 528	V10UTPUT	DS DS	XL16 FD				
3000000				529				gap			
				530 531		test	routine will be here	(from VRR-a macro)			
				532		follo	wed by				
				533			EXPECTED RESULT				

ASMA Ver.	0. 7. 0 zvector- e7	-06-Find (Zv	ector E7 V	RR-a i	nstructi	on)		12 Feb 2025 14: 26: 16 Page 13
LOC	OBJECT CODE	ADDR1	ADDR2	STM				
		0000000			ZVE7TST	CSECT		
00001118		0000000	UUUULDJI	536	ZVE/131		, 0F	
				538	*****	*****	*******	**********
				539 540	* Ma *****	cros to	nelp build test	tabl es **********
				542				
				543 544		to gene	erate individual t	est
				545		MACRO		
				546 547	*	VKK_A	&I NST, &MB, &M5, &CC	&INST - VRR-a instruction under test
				548 549	*			&MB - MB field - element size &M5 - M5 field - CS
				550				&CC - expected CC
				551 552		ICIA	&XCC(4) &XCC has	mask values for FAILED condition codes
				553	&XCC(1)	SETA	7	CC != 0
					&XCC(2) &XCC(3)	SETA SETA		CC != 1 CC != 2
				556	&XCC(4)	SETA		CC != 3
				557 558		GBLA	&TNUM	
				559	&TNUM		&TNUM+1	
				560 561		DS	OFD	
				562 563		USING	*, R 5	base for test data and test routine
				564	T&TNUM		A(X&TNUM)	address of test routine
				565 566		DC DC	H' &TNUM' X' 00'	test number
				567		DC	HL1'&MB'	M3 used
				568 569		DC	HL1' &M5' HL1' &CC'	M5 used CC
				570 571		DC	HL1' &XCC(&CC+1)'	CC failed mask
				572		DS	2F	extracted PSW after test (has CC)
				573 574		DC	X' FF'	extracted CC, if test failed
				575		DC	CL8' &INST'	instruction name
				576 577		DC DC	A(RE&TNUM) A(RE&TNUM+16)	address of v1 result address of v2 source
				578 579		DC DC	A(RE&TNUM+32) A(16)	address of v3 source
				580	REA&TNUM	I DC	A (RE&TNUM)	result length result address
				581 582	V10&TNUM	DS I DS	FD XL16	gap V1 output
				583		DS	FD	gap
				584 585				
				586	X&TNUM	DS I A	OF	load v21 fudgo
				587 588			R1, V1FUDGE v21, O(R1)	load v21 fudge

		-			i on)		12 Feb 2025 14: 26: 16 Page
LOC	OBJECT CODE	ADDR1	ADDR2	STMI			

				631 *	E7 VR	R-a tests	***********
				633	PRINT		
				634 *	1 101111	Dilli	
				635 *			
				636 * E75 637 *	C VISTR	- Vector Iso	late String
				638 *	VRR- a	instruction,	
				639 *	V 1010 C1	MB,	element size
				640 *		M5 ,	CS
				641 * 642 *		CC	expected condition code
				643 *		followed by	
				644 *		16 byte V1	result
				645 *		16 byte V2	source
				646 647 *			
				648 * VISTR	- Vect	tor Isolate St	ri ng
				650 651 *			
				652 * case		mole debug	CS=1
				653 *			
				654 *byte	VDD A	VICTD O 1 O	
001118				655 656+	DS VKK_A	VI STR, 0, 1, 0 OFD	
001118		00001118		657 +	USI NG		base for test data and test routine
001118	00001170			658+T1	DC	A(X1)	address of test routine
00111C 00111E	0001			659+ 660+	DC DC		test number
00111E				661+	DC	HL1' 0'	M3 used
001120				662+	DC	HL1' 1'	M5 used
001121				663+	DC	HL1' 0'	CC CC failed mask
001122 001124	07 0000000 00000000			664+ 665+	DC DS	HL1' 7' 2F	extracted PSW after test (has CC)
00112C	FF			666+	DC	X' FF'	extracted CC, if test failed
00112D	E5C9E2E3 D9404040			667+	DC	CL8' VI STR'	instruction name
001138 00113C	0000119C 000011AC			668+ 669+	DC DC	A(RE1) A(RE1+16)	address of v1 result address of v2 source
001130	000011AC 000011BC			670+	DC	A(RE1+10) $A(RE1+32)$	address of v2 source
001144	0000010			671 +	DC	A(16)	result length
001148	0000119C			672+REA1	DC	A(RE1)	result address
001150 001158	0000000 0000000 0000000 0000000			673+ 674+V101	DS DS	FD XL16	gap V1 output
001160	0000000 0000000			07117101	D.O		11 ouchuc
001168	00000000 00000000			675+	DS	FD	gap
001170				676+* 677+X1	DS	OF	
01170	4110 8EF8		000010F8	678+	LA	R1, V1FUDGE	load v21 fudge
001174	E751 0000 0806		0000000	679 +	VL	v21, 0(R1)	Q
00117A	E310 5024 0014		00000024	680+	LGF	R1, V2ADDR	load v2 source
001180 001186	E761 0000 0806 E756 0010 0C5C		0000000	681+ 682+	VL VISTR	v22, 0(R1) V21, V22, 0, 1	use v21 to test decoder test instruction
00118C	B98D 0020			683+		R2, R0	extract psw
	5020 500C		000000C	684+	ST	R2, CCPSW	to save CC

DC

DC

734+

735 +

0000126E

0000126F

00

00

X' 00'

HL1' 0'

MB used

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001270 00001271	01 03			736+ 737+	DC DC	HL1' 1' HL1' 3'	M5 used CC
00001272 00001274 0000127C	0E 00000000 00000000 FF			738+ 739+ 740+	DC DS DC	HL1' 14' 2F X' FF'	CC failed mask extracted PSW after test (has CC) extracted CC, if test failed
0000127D 00001288	E5C9E2E3 D9404040 000012EC			741+ 742+	DC DC	CL8' VI STR' A(RE3)	instruction name address of v1 result
0000128C 00001290 00001294	000012FC 0000130C 00000010			743+ 744+ 745+	DC DC DC	A(RE3+16) A(RE3+32) A(16)	address of v2 source address of v3 source result length
00001298 000012A0 000012A8	000012EC 00000000 00000000 00000000 00000000			746+REA3 747+ 748+V103	DC DS DS	A(RE3) FD XL16	result address gap V1 output
000012A8 000012B0 000012B8	0000000 0000000 00000000 00000000 000000			749 +	DS	FD	gap
000012C0 000012C0	4110 8EF8		000010F8	750+* 751+X3 752+	DS LA	OF R1, V1FUDGE	load v21 fudge
000012C4 000012CA	E751 0000 0806 E310 5024 0014		00000000 0000024	753+ 754+	VL LGF	v21, 0(R1) R1, V2ADDR	load v2 source
000012D0 000012D6 000012DC	E761 0000 0806 E756 0010 0C5C B98D 0020	(00000000	755+ 756+ 757+	VL VI STR EPSW	v22, 0(R1) V21, V22, 0, 1 R2, R0	use v21 to test decoder test instruction extract psw
000012E0 000012E4 000012EA	5020 500C E750 5040 080E 07FB		0000000C 000012A8	758+ 759+ 760+	ST VST BR	R2, CCPSW V21, V103 R11	to save CC save v1 output return
000012EC 000012EC				761+RE3 762+	DC DROP	0F R5	V1 for this test
000012EC 000012F4 000012FC 00001304	01020304 05060708 090A0B0C 0D0E0F10 01020304 05060708 090A0B0C 0D0E0F10			763 764	DC DC		05060708 090A0B0C 0D0E0F10' v1 05060708 090A0B0C 0D0E0F10' v2

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				766 *halfwor	d		
				767		VI STR, 1, 1, 0	
00001310				768+	DS	OFD	
00001310		00001310		769 +	USING	*, R5	base for test data and test routine
00001310	00001368			770+T4	DC	A(X4)	address of test routine
00001314	0004			771+	DC	H' 4'	test number
00001316	00			772+	DC	X' 00'	MD J
00001317	01 01			773+ 774+	DC DC	HL1' 1' HL1' 1'	M3 used M5 used
00001318 00001319	00			774+ 775+	DC DC	HL1' 0'	CC Wb used
00001313 0000131A	07			776+	DC DC	HL1' 7'	CC failed mask
0000131C	00000000 00000000			777+	DS	2F	extracted PSW after test (has CC)
00001324	FF			778+	DC	X' FF'	extracted CC, if test failed
00001325	E5C9E2E3 D9404040			779+	DC	CL8' VISTR'	instruction name
00001330	00001394			780+	DC	A(RE4)	address of v1 result
00001334	000013A4			781+	DC	A(RE4+16)	address of v2 source
00001338 0000133C	000013B4			782+ 783+	DC DC	A(RE4+32)	address of v3 source
00001330	00000010 00001394			784+REA4	DC DC	A(16) A(RE4)	result length result address
00001340	00001334			785+	DS DS	FD	gap
00001350	00000000 00000000			786+V104	DS	XL16	V1 output
00001358	0000000 00000000						,
00001360	0000000 00000000			787 +	DS	FD	gap
				788+*		~ ~	
00001368	4440 OFFO		00001000	789+X4	DS	OF	1 1 04 6 1
00001368 0000136C	4110 8EF8 E751 0000 0806		000010F8 00000000	790+ 791+	LA	R1, V1FUDGE	load v21 fudge
00001360	E310 5024 0014		0000000	791+ 792+	VL LGF	v21, 0(R1) R1, V2ADDR	load v2 source
00001372	E761 0000 0806		00000004	793+	VL	v22, 0(R1)	use v21 to test decoder
0000137E	E756 0010 1C5C			794+	VISTR	V21, V22, 1, 1	test instruction
00001384	B98D 0020			795 +	EPSW	R2, R0	extract psw
00001388	5020 500C		000000C	796+	ST	R2, CCPSW	to save CC
0000138C	E750 5040 080E		00001350	797+	VST	V21, V104	save v1 output
00001392	07FB			798+ 799+RE4	BR DC	R11 0F	return V1 for this tost
00001394 00001394				799+RE4 800+	DROP	R5	V1 for this test
00001394	00000000 00000000			801	DC		00000000 00000000 00000000' V1
0000139C	0000000 00000000			001	20	ALIO OUGOOOG	11
000013A4	0000000 00000000			802	DC	XL16' 00000000	00000000 00000000 00000000' v2
000013AC	0000000 00000000						
				803	T/DD 4	TIT CITED 4 4 0	
00001200				804		VISTR, 1, 1, 0	
000013B8 000013B8		000013B8		805+ 806+	DS USING	0FD * P5	base for test data and test routine
000013B8	00001410	00001300		807+T5	DC	A(X5)	address of test routine
000013BC	0005			808+	DC	H' 5'	test number
000013BE	00			809 +	DC	X' 00'	
000013BF	01			810+	DC	HL1' 1'	MB used
000013C0	01			811+	DC	HL1' 1'	M5 used
000013C1	00			812+	DC	HL1'0'	CC CC foiled made
000013C2 000013C4	07 00000000 00000000			813+ 814+	DC DS	HL1' 7' 2F	CC failed mask extracted PSW after test (has CC)
000013C4 000013CC	FF			815+	DC DC	X' FF'	extracted rsw arter test (has cc) extracted CC, if test failed
000013CD	E5C9E2E3 D9404040			816+	DC	CL8' VISTR'	instruction name
000013D8	0000143C			817+	DC	A(RE5)	address of v1 result
000013DC	0000144C			818+	DC	A(RE5+16)	address of v2 source

R2, CCPSW

to save CC

5020 500C

000014D8

000000C

870 +

ISMA VEI.	0.7.0 200	ector - e7 - 0	O-Tina (Zv	ector E7	vin-a instruct	1011)		12 Teb 2020 14. 20. 10 Tage
LOC	OBJECT	CODE	ADDR1	ADDR2	STMT			
					878 *word			
					879		VISTR, 2, 1, 0	
0001508					880+	DS _	OFD	
0001508			00001508		881 +	USING		base for test data and test routine
0001508	00001560				882+T7	DC	A(X7)	address of test routine
000150C	0007				883+	DC	H' 7'	test number
00150E	00				884+	DC	X' 00'	cose number
00150E	02				885+	DC	HL1'2'	MB used
001501	01				886+	DC	HL1' 1'	M5 used
001510	00				887+	DC	HL1' 0'	CC
001512	07	000000			888+	DC	HL1' 7'	CC failed mask
001514	00000000 0	0000000			889+	DS	2F	extracted PSW after test (has CC)
00151C	FF				890+	DC	X' FF'	extracted CC, if test failed
00151D	E5C9E2E3 D	9404040			891+	DC	CL8' VISTR'	instruction name
0001528	0000158C				892+	DC	A(RE7)	address of v1 result
000152C	0000159C				893+	DC	A(RE7+16)	address of v2 source
0001530	000015AC				894 +	DC	A(RE7+32)	address of v3 source
0001534	00000010				895+	DC	A(16)	result length
001538	0000158C				896+REA7	DC	A(RE7)	result address
001540	00000000 0	0000000			897+	DS	FD	
001548	00000000 0				898+V107	DS	XL16	gap V1 output
					030+1107	DЗ	ALIU	vi oucpuc
0001550	00000000				000	DC	ED	
0001558	00000000	0000000			899+	DS	FD	gap
					900+*	~ ~	.=	
0001560					901+X7	DS	0F	
0001560	4110 8EF8			000010F8	902+	LA	R1, V1FUDGE	load v21 fudge
0001564	E751 0000			00000000	903+	VL	v21, 0(R1)	
000156A	E310 5024	0014		00000024	904+	LGF	R1, V2ADDR	load v2 source
0001570	E761 0000	0806		0000000	905+	\mathbf{VL}	v22, 0(R1)	use v21 to test decoder
0001576	E756 0010				906+		V21, V22, 2, 1	test instruction
000157C	B98D 0020	2000			907+	EPSW	R2, R0	extract psw
001570	5020 500C			000000C	908+	ST	R2, CCPSW	to save CC
001584	E750 5040	USUE		00001548	909+	VST	V21, V107	
		UOUE		00001346				save v1 output
000158A	07FB				910+	BR	R11	return
000158C					911+RE7	DC	OF	V1 for this test
000158C					912+	DROP	R5	
000158C	00000000				913	DC	XL16' 00000000	00000000 00000000 00000000' V1
0001594	00000000 0	0000000						
000159C	00000000 0	0000000			914	DC	XL16' 00000000	00000000 00000000 00000000' v2
00015A4	00000000	0000000						
					915			
					916	VRR A	VISTR, 2, 1, 0	
00015B0					917+	DS DS	OFD	
0015B0			000015B0		918+	USING		base for test data and test routine
)0015B0	00001608		00001300		919+T8	DC		address of test routine
							A(X8)	
00015B4	0008				920+	DC	H' 8'	test number
00015B6	00				921+	DC	X' 00'	
0015B7	02				922+	DC	HL1' 2'	MB used
00015B8	01				923+	DC	HL1' 1'	M5 used
00015B9	00				924+	DC	HL1' 0'	CC
00015BA	07				925+	DC	HL1' 7'	CC failed mask
00015BC	00000000 0	0000000			926+	DS	2F	extracted PSW after test (has CC)
00015C4	FF				927+	DC	X' FF'	extracted CC, if test failed
00015C4	E5C9E2E3 D	9404040			928+	DC	CL8' VISTR'	instruction name
00015C5 00015D0	00001634	J4U4U4U			929+	DC DC	A(RE8)	address of v1 result
00015D4	00001644				930+	DC	A(RE8+16)	address of v2 source

ASIM VEI.	0. 7. 0 zvector- e / - 0	JO-TING (ZV	cccor Er v	www a linstruct	011)		12 Feb 2025 14: 26: 16 Page	22
LOC	OBJECT CODE	ADDR1	ADDR2	STMF				
LUC	OBJECT CODE	ADDKI	ADDIK	SIM				
000015D8	00001654			931+	DC	A(RE8+32)	address of v3 source	
000015DC	00000010			932+	DC	A(16)	result length	
000015E0	00001634			933+REA8	DC	A(RE8)	result address	
000015E8	00000000 00000000			934+	DS	FD		
000015E0	0000000 00000000			935+V108	DS	XL16	gap V1 output	
000015F8	0000000 0000000			00011100		ALIU	VI oucpue	
00001600	0000000 00000000			936+	DS	FD	gap	
00001000				937+*	22		8"r	
00001608				938+X8	DS	0F		
00001608	4110 8EF8		000010F8	939+	LA	R1, V1FUDGE	load v21 fudge	
0000160C	E751 0000 0806		00000000	940+	VL	v21, 0(R1)	8	
00001612	E310 5024 0014		00000024	941+	LGF	R1, V2ÀDDR	load v2 source	
00001618	E761 0000 0806		00000000	942+	VL	v22, 0(R1)	use v21 to test decoder	
0000161E	E756 0010 2C5C			943+	VISTR	V21, V22, 2, 1	test instruction	
00001624	B98D 0020			944+		R2, R0	extract psw	
00001628	5020 500C		000000C	945+	ST	R2, CCPSW	to save CC	
0000162C	E750 5040 080E		000015F0	946+	VST	V21, V108	save v1 output	
00001632	07FB			947+	BR	R11	return	
00001634				948+RE8	DC	0F	V1 for this test	
00001634				949+	DROP	R5		
00001634	10203040 00000000			950	DC	XL16' 01020304	00000000 00000000 000000000' V1	
0000163C	00000000 00000000							
00001644	10203040 00000000			951	DC	XL16' 01020304	00000000 OFFFFFF FFFFFFFF v2	
0000164C	FFFFFFF FFFFFFF			0.40				
				952		TIT CITTO O 4 O		
				069		VICTO 9 1 9		
00001050				953		VISTR, 2, 1, 3		
00001658		00001070		954+	DS	OFD	have Contract data and tract months	
00001658	00001670	00001658		954+ 955+	DS USI NG	0FD *, R5	base for test data and test routine	
00001658 00001658	000016B0	00001658		954+ 955+ 956+T9	DS USI NG DC	0FD *, R5 A(X9)	address of test routine	
00001658 00001658 0000165C	0009	00001658		954+ 955+ 956+T9 957+	DS USING DC DC	OFD *, R5 A(X9) H' 9'		
00001658 00001658 0000165C 0000165E	0009 00	00001658		954+ 955+ 956+T9 957+ 958+	DS USING DC DC DC	OFD *, R5 A(X9) H' 9' X' 00'	address of test routine test number	
00001658 00001658 0000165C 0000165E 0000165F	0009 00 02	00001658		954+ 955+ 956+T9 957+ 958+ 959+	DS USING DC DC DC DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2'	address of test routine test number MB used	
00001658 00001658 0000165C 0000165E 0000165F 00001660	0009 00 02 01	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+	DS USING DC DC DC DC DC DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1'	address of test routine test number MB used M5 used	
00001658 00001658 0000165C 0000165E 0000166F 00001660 00001661	0009 00 02 01 03	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+	DS USING DC DC DC DC DC DC DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3'	address of test routine test number MB used M5 used CC	
00001658 00001658 0000165C 0000165E 0000166F 00001660 00001661	0009 00 02 01 03 0E	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+	DS USING DC DC DC DC DC DC DC DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 1' HL1' 3' HL1' 14'	address of test routine test number MB used M5 used CC CC failed mask	
00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664	0009 00 02 01 03 0E 00000000 00000000	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC)	
00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C	0009 00 02 01 03 0E 00000000 00000000 FF	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF'	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed	
00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664	0009 00 02 01 03 0E 00000000 00000000	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR'	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC)	
00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF'	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name	
00001658 00001658 0000165C 0000165E 00001660 00001661 00001662 00001664 0000166C 0000166D	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result	
00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 00001678 0000167C	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016EC	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+	DS USING DC	0FD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source	
00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016EC 000016FC	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+	DS USING DC	0FD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source	
00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680 00001684 00001688	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016EC 000016FC	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 966+ 967+ 968+ 969+ 970+REA9 971+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address	
00001658 0000165E 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001698	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000000 00000000 00000000 00000000	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 966+ 967+ 968+ 969+	DS USING DC	0FD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address	
00001658 0000165E 0000165E 0000165F 00001660 00001661 00001662 0000166C 0000166D 0000167C 00001680 00001688 00001688 00001690 00001698	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 969+ 970+REA9 971+ 972+V109	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length	
00001658 0000165E 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001698	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000000 00000000 00000000 00000000	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 970+ 970+ 970+ 971+ 972+V109	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address	
00001658 0000165C 0000165E 0000165E 00001660 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001690 000016A0 000016A0	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 969+ 970+REA9 971+ 972+V109	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output	
00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001662 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001690 000016A0 000016A0	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000 000000	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 969+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD OF	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap	
00001658 0000165C 0000165E 0000165E 0000166D 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001698 000016A0 000016A0	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000 000000	00001658	000010F8	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9 976+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD OF R1, V1FUDGE	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output	
00001658 0000165C 0000165E 0000165E 0000166D 00001661 00001662 0000166C 0000166D 0000167C 0000168D 00001684 00001688 00001690 00001698 000016A0 000016B0 000016B0 000016B0	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000016 000016DC 0000000 0000000 0000000 0000000 0000000	00001658	00000000	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9 976+ 977+	DS USING DC	0FD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD OF R1, V1FUDGE v21, O(R1)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge	
00001658 0000165C 0000165E 0000165E 0000166D 00001661 00001662 0000166C 0000166D 0000167C 0000168D 00001688 00001688 00001690 00001698 000016A0 000016B0 000016B0 000016B4 000016B4	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000016 000016DC 0000000 00000000 0000000 00000000 000000	00001658	00000000 00000024	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9 976+ 977+ 978+	DS USING DC	0FD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD OF R1, V1FUDGE v21, O(R1) R1, V2ADDR	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge load v2 source	
00001658 0000165C 0000165E 0000165E 00001660 00001661 00001662 00001662 0000166C 0000166D 0000167C 00001680 00001688 00001688 00001690 00001698 000016A0 000016A0 000016B0 000016B0 000016BA 000016BA	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016EC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000 000000	00001658	00000000	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9 976+ 978+ 979+	DS USING DC	0FD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD 0F R1, V1FUDGE v21, O(R1) R1, V2ADDR v22, O(R1)	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge load v2 source use v21 to test decoder	
00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001690 000016A0 000016B0 000016B0 000016BA 000016BA 000016CO 000016CO	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016EC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000 000000	00001658	00000000 00000024	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9 976+ 977+ 978+ 979+ 980+	DS USING DC	0FD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD 0F R1, V1FUDGE v21, 0(R1) R1, V2ADDR v22, 0(R1) V21, V22, 2, 1	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge load v2 source use v21 to test decoder test instruction	
00001658 0000165C 0000165E 0000165E 00001660 00001661 00001662 00001662 0000166C 0000166D 0000167C 00001680 00001688 00001688 00001690 00001698 000016A0 000016A0 000016B0 000016B0 000016BA 000016BA	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016EC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000 000000	00001658	00000000 00000024	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9 976+ 978+ 979+	DS USING DC	0FD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD 0F R1, V1FUDGE v21, O(R1) R1, V2ADDR v22, O(R1)	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge load v2 source use v21 to test decoder	

DC

DC

DS

DC

HL1'0'

HL1'7'

X' FF'

2F

CC

CC failed mask

extracted PSW after test (has CC)

extracted CC, if test failed

1039 +

1040 +

1041+

1042 +

00

07

0000000 00000000

000017B1 000017B2

000017B4

000017BC

ASMA Ver.	0. 7. 0 zvector- e7- 0	06-Find (Zv	ector E7 V	RR-a instructi	on)		12 Feb 2025 14: 26: 16 Page	25
LOC	OBJECT CODE	ADDR1	ADDR2	STMF				
000017BD	E5C9E2E3 D9404040			1043+	DC	CL8' VISTR'	instruction name	
000017C8	0000182C			1044+	DC	A(RE11)	address of v1 result	
000017CC	0000183C			1045+	DC DC	A(RE11+16)	address of v2 source	
000017D0 000017D4	0000184C 00000010			1046+ 1047+	DC DC	A(RE11+32) A(16)	address of v3 source result length	
000017D4 000017D8	0000010 0000182C			1047+ 1048+REA11	DC	A(RE11)	result address	
000017E0	00000000 00000000			1049+ 1049+	DS	FD		
000017E8	0000000 00000000			1050+V1011	DS	XL16	gap V1 output	
000017F0	00000000 00000000							
000017F8	00000000 00000000			1051+	DS	FD	gap	
				1052+*			~ -	
00001800	4440 0770		00004070	1053+X11	DS	OF		
00001800	4110 8EF8		000010F8	1054+	LA	R1, V1FUDGE	load v21 fudge	
00001804 0000180A	E751 0000 0806 E310 5024 0014		00000000 0000024	1055+	VL LGF	v21, 0(R1)	load v9 gaunas	
0000180A 00001810	E761 0000 0806		00000024	1056+ 1057+	LGF VL	R1, V2ADDR v22, O(R1)	load v2 source use v21 to test decoder	
00001816	E756 0010 0C5C		0000000	1058+	VL	V21, V22, 0, 1	test instruction	
0000181C	B98D 0020			1059+	EPSW	R2, R0	extract psw	
00001820	5020 500C		000000C	1060+	ST	R2, CCPSW	to save CC	
00001824	E750 5040 080E		000017E8	1061+	VST	V21, V1011	save v1 output	
0000182A	07FB			1062+	BR	R11	return	
0000182C				1063+RE11	DC	0F	V1 for this test	
0000182C	01000001 0500000			1064+	DROP	R5	05000500 00010000 000000000	
0000182C	01020304 05060708			1065	DC	XL16' 01020304	05060708 090A0B0C 0D0E0F00' v1	
00001834 0000183C	090A0B0C 0D0E0F00 01020304 05060708			1066	DC	VI 16! 01090904	05060708 090A0B0C 0D0E0F00' v2	
				1000	ъс	ALIO OTOROGOT	00000700 000Noboc obollo100 V2	
00001830	O9OAOBOC ODOEOFOO			1067	Do	NEIO 01020001	V2	
						VI STR, 0, 1, 0	V2	
00001844 00001850				1067 1068 1069+	VRR_A DS	VI STR, 0, 1, 0 OFD		
00001844 00001850 00001850	O9OAOBOC ODOEOFOO	00001850		1067 1068 1069+ 1070+	VRR_A DS USING	VI STR, 0, 1, 0 OFD *, R5	base for test data and test routine	
00001844 00001850 00001850 00001850	090A0B0C 0D0E0F00 000018A8	00001850		1067 1068 1069+ 1070+ 1071+T12	VRR_A DS USING DC	VI STR, 0, 1, 0 OFD *, R5 A(X12)	base for test data and test routine address of test routine	
00001844 00001850 00001850 00001850 00001854	090A0B0C 0D0E0F00 000018A8 000C	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+	VRR_A DS USING DC DC	VI STR, 0, 1, 0 OFD *, R5 A(X12) H' 12'	base for test data and test routine	
00001844 00001850 00001850 00001854 00001856	090A0B0C 0D0E0F00 000018A8 000C 00	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+	VRR_A DS USING DC DC DC	VI STR, 0, 1, 0 OFD *, R5 A(X12) H' 12' X' 00'	base for test data and test routine address of test routine test number	
00001844 00001850 00001850 00001854 00001856 00001857	090A0B0C 0D0E0F00 000018A8 000C 00 00	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+	VRR_A DS USING DC DC DC DC	VI STR, 0, 1, 0 OFD *, R5 A(X12) H' 12' X' 00' HL1' 0'	base for test data and test routine address of test routine test number M3 used	
00001844 00001850 00001850 00001854 00001856 00001857 00001858	090A0B0C 0D0E0F00 000018A8 000C 00 00 01	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+	VRR_A DS USING DC DC DC DC DC	VI STR, 0, 1, 0 OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1'	base for test data and test routine address of test routine test number M3 used M5 used	
00001844 00001850 00001850 00001854 00001856 00001857	090A0B0C 0D0E0F00 000018A8 000C 00 00	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+	VRR_A DS USING DC DC DC DC	VI STR, 0, 1, 0 OFD *, R5 A(X12) H' 12' X' 00' HL1' 0'	base for test data and test routine address of test routine test number M3 used	
00001844 00001850 00001850 00001854 00001856 00001857 00001858 00001859 0000185A	090A0B0C 0D0E0F00 000018A8 000C 00 00 01 00 07 00000000 00000000	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+	VRR_A DS USI NG DC DC DC DC DC DC DC DC	VI STR, 0, 1, 0 OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 1' HL1' 7' 2F	base for test data and test routine address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC)	
00001844 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864	090A0B0C 0D0E0F00 000018A8 000C 00 00 01 00 07 00000000 00000000 FF	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+	VRR_A DS USI NG DC	VI STR, 0, 1, 0 OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF'	base for test data and test routine address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed	
00001844 00001850 00001850 00001854 00001856 00001857 00001858 00001859 0000185C 00001864 00001865	090A0B0C 0D0E0F00 000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+	VRR_A DS USI NG DC	VISTR, 0, 1, 0 0FD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VISTR'	base for test data and test routine address of test routine test number M3 used M5 used CC CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name	
00001844 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001865 00001870	090A0B0C 0D0E0F00 000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+	VRR_A DS USING DC	VISTR, 0, 1, 0 0FD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VISTR' A(RE12)	base for test data and test routine address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result	
00001844 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001865 00001870 00001874	090A0B0C 0D0E0F00 000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018E4	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+ 1082+	VRR_A DS USING DC	VISTR, 0, 1, 0 OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VISTR' A(RE12) A(RE12+16)	base for test data and test routine address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source	
00001844 00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001870 00001874 00001878	090A0B0C 0D0E0F00 000018A8 000C 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018F4	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+ 1082+ 1083+	VRR_A DS USI NG DC	VI STR, 0, 1, 0 OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+16) A(RE12+32)	base for test data and test routine address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source	
00001844 00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001870 00001874 00001878	090A0B0C 0D0E0F00 000018A8 000C 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018E4 000018F4 0000010	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+ 1082+ 1083+ 1084+	VRR_A DS USI NG DC	VI STR, 0, 1, 0 0FD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+16) A(RE12+32) A(16)	base for test data and test routine address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length	
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00001844 00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001865 00001870 00001878 00001870 00001870 00001880 00001880 00001880	090A0B0C 0D0E0F00 000018A8 000C 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018F4 0000018D4 0000018D4 0000018D4 000000000000000000000000000000000000	00001850		1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1079+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12 1086+ 1087+V1012	VRR_A DS USI NG DC	VISTR, 0, 1, 0 0FD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VISTR' A(RE12) A(RE12+16) A(RE12+32) A(16) A(RE12) FD	base for test data and test routine address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address	
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00001844 00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001870 00001874 00001878 00001870 00001878 00001880 00001880 00001880 00001880 00001880	090A0B0C 0D0E0F00 000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018E4 000018F4 0000010 000018D4 0000010 000018D4 00000000 00000000 00000000 0000000000	00001850	ΟΟΟΟ 1 Ο ΕΩ	1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12 1086+ 1087+V1012	VRR_A DS USI NG DC	VI STR, 0, 1, 0 OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+16) A(RE12+32) A(16) A(RE12) FD XL16 FD OF	base for test data and test routine address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap	
00001844 00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001865 00001870 00001870 00001870 00001870 00001870 00001880 00001880 00001880 00001888	090A0B0C 0D0E0F00 000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018F4 0000018F4 0000018D4 0000018D4 0000000 00000000 00000000 00000000 000000	00001850	000010F8 00000000	1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12 1086+ 1087+V1012	VRR_A DS USI NG DC	VI STR, 0, 1, 0 0FD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+16) A(RE12+32) A(16) A(RE12) FD XL16 FD OF R1, V1 FUDGE	base for test data and test routine address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output	
00001844 00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001870 00001874 00001878 00001870 00001878 00001880 00001880 00001880 00001880 00001880	090A0B0C 0D0E0F00 000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018E4 000018F4 0000010 000018D4 0000010 000018D4 00000000 00000000 00000000 0000000000	00001850	000010F8 00000000 00000024	1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12 1086+ 1087+V1012	VRR_A DS USI NG DC	VISTR, 0, 1, 0 0FD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VISTR' A(RE12) A(RE12+16) A(RE12+32) A(16) A(RE12) FD XL16 FD OF R1, V1FUDGE v21, 0(R1)	base for test data and test routine address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap	
00001844 00001850 00001850 00001850 00001854 00001857 00001858 00001858 0000185A 0000185C 00001864 00001865 00001870 00001870 00001870 00001870 00001880 00001880 00001880 00001888	090A0B0C 0D0E0F00 000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018F4 000018F4 0000018D4 0000018D4 0000000 00000000 00000000 00000000 000000	00001850	00000000	1067 1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1079+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12 1086+ 1087+V1012	VRR_A DS USI NG DC	VI STR, 0, 1, 0 0FD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+16) A(RE12+32) A(16) A(RE12) FD XL16 FD OF R1, V1 FUDGE	base for test data and test routine address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge	

ASMA Ver.	0. 7. 0 zvector- e7- 0	6-Find (Zve	ector E7 V	RR-a instructi	on)		12 Feb 2025 14: 26: 16 Pag	e 26
LOC	OBJECT CODE	ADDR1	ADDR2	STMI				
000018BE 000018C4 000018C8	E756 0010 0C5C B98D 0020 5020 500C		0000000C	1095+ 1096+ 1097+	VI STR EPSW ST	V21, V22, 0, 1 R2, R0 R2, CCPSW	test instruction extract psw to save CC	
000018CC 000018D2			00000000	1098+ 1099+	VST BR	V21, V1012 R11	save v1 output return	
000018D4 000018D4 000018D4	01020304 05060708			1100+RE12 1101+ 1102	DC DROP DC	OF R5 XL16' 01020304	V1 for this test 05060708 090A0B0C 0D000000' v1	
000018DC 000018E4				1103	DC		05060708 090A0B0C 0D000F10' v2	
000018F8				1104 1105 1106+	VRR_A DS	VI STR, 0, 1, 0 OFD		
000018F8 000018F8 000018FC	00001950 000D	000018F8		1107+ 1108+T13 1109+	USI NG DC DC		base for test data and test routine address of test routine test number	
000018FE 000018FF 00001900	00 00			1110+ 1111+ 1112+	DC DC DC	X' 00' HL1' 0' HL1' 1'	MB used M5 used	
00001901 00001902 00001904	00 07			1113+ 1114+ 1115+	DC DC DS	HL1' 0' HL1' 7' 2F	CC CC failed mask extracted PSW after test (has CC)	
0000190C 0000190D	FF E5C9E2E3 D9404040			1116+ 1117+	DC DC	X' FF' CL8' VI STR'	extracted CC, if test failed instruction name	
00001918 0000191C 00001920	0000198C 0000199C			1118+ 1119+ 1120+	DC DC DC	A(RE13) A(RE13+16) A(RE13+32)	address of v1 result address of v2 source address of v3 source	
00001924 00001928 00001930	00000000 00000000			1121+ 1122+REA13 1123+	DC DC DS	A(16) A(RE13) FD	result length result address gap	
00001938 00001940 00001948	00000000 00000000			1124+V1013 1125+	DS DS	XL16 FD	V1 output gap	
00001950 00001950	4110 8EF8		000010F8	1126+* 1127+X13 1128+	DS LA	OF R1, V1FUDGE	load v21 fudge	
00001954 0000195A 00001960	E751 0000 0806 E310 5024 0014 E761 0000 0806		00000000 00000024 00000000	1130+ 1131+	VL LGF VL	v21, 0(R1) R1, V2ADDR v22, 0(R1)	load v2 source use v21 to test decoder	
00001966 0000196C 00001970	E756 0010 0C5C B98D 0020 5020 500C		000000C	1132+ 1133+ 1134+	EPSW ST	V21, V22, 0, 1 R2, R0 R2, CCPSW	test instruction extract psw to save CC	
00001974 0000197A 0000197C	E750 5040 080E 07FB		00001938	1135+ 1136+ 1137+RE13	VST BR DC	V21, V1013 R11 OF	save v1 output return V1 for this test	
0000197C 0000197C 00001984	01020304 05060708 090A0B0C 00000000			1138+ 1139	DROP DC	R5	05060708 090A0B0C 00000000' v1	
				1140 1141	DC	XL16' 01020304	05060708 090A0B0C 000E0F10' v2	
000019A0				1141 1142 1143+	DS	VI STR, 0, 1, 0 OFD		
000019A0 000019A0	000019F8	000019A0		1144+ 1145+T14	USI NG DC	*, R5 A(X14)	base for test data and test routine address of test routine	

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LOC	OBJECT CODE	ADDR1	ADDR2	STMI			
000019A4	000E			1146+	DC	H' 14'	test number
000019A4	00			1147+	DC	X' 00'	cest number
000019A7	00			1148+	DC	HL1' 0'	MB used
000019A7	01			1149+	DC	HL1' 1'	M5 used
000019A9	00			1145+ 1150+	DC	HL1' 0'	CC
000019A3	07			1151+	DC	HL1' 7'	CC failed mask
000019AC	00000000 00000000			1152+	DS	2F	extracted PSW after test (has CC)
000019RC	FF			1153+	DC	X' FF'	extracted CC, if test failed
000013B4	E5C9E2E3 D9404040			1154+	DC	CL8' VISTR'	instruction name
000019E0	00001A24			1155+	DC	A(RE14)	address of v1 result
000019C4	00001A34			1156+	DC	A(RE14+16)	address of v2 source
000019C8	00001A44			1157+	DC	A(RE14+32)	address of v3 source
000019CC	00000010			1158+	DC	A(16)	result length
000019D0	00001A24			1159+REA14	DC	A(RE14)	result address
000019D8	0000000 00000000			1160+	DS	FĎ	
000019E0	0000000 00000000			1161+V1014	DS	XL16	gap V1 output
000019E8	0000000 00000000						•
000019F0	0000000 00000000			1162+	DS	FD	gap
				1163+*			.
000019F8				1164+X14	DS	0F	
000019F8	4110 8EF8		000010F8	1165+	LA	R1, V1FUDGE	load v21 fudge
000019FC	E751 0000 0806		00000000	1166+	VL	v21, 0(R1)	
00001A02	E310 5024 0014		00000024	1167+	LGF	R1, V2ADDR	load v2 source
00001A08	E761 0000 0806		00000000	1168+	VL	v22, 0(R1)	use v21 to test decoder
00001A0E	E756 0010 0C5C			1169+	VISTR	V21, V22, 0, 1	test instruction
00001A14	B98D 0020		0000000	1170+		R2, R0	extract psw
00001A18	5020 500C		000000C	1171+	ST	R2, CCPSW	to save CC
00001A1C	E750 5040 080E		000019E0	1172+	VST	V21, V1014	save v1 output
00001A22	07FB			1173+	BR DC	R11 OF	return V1 for this test
00001A24 00001A24				1174+RE14 1175+	DROP	R5	vi for this test
00001A24	01020304 05060708			1176	DKOF		05060708 090A0B00 00000000' v1
00001A24	090A0B00 00000000			1170	ЪС	ALIU UIU2UJU4	03000700 030A0D00 00000000 V1
00001A2C	01020304 05060708			1177	DC	XI 16' 01020304	05060708 090A0B00 0D0E0F10' v2
	090A0B00 0D0E0F10			11//	ВС	ALIO OIO20001	00000700 000M0D00 0D0L0110 V2
000011100	000110200 02020110			1178			
				1179	VRR A	VISTR, 0, 1, 0	
00001A48				1180+	DS	OFD	
00001A48		00001A48		1181+	USING		base for test data and test routine
00001A48	00001AA0			1182+T15	DC	A(X15)	address of test routine
00001A4C	000F			1183+	DC	H' 15'	test number
00001A4E	00			1184+	DC	X' 00'	
00001A4F	00			1185+	DC	HL1' 0'	MB used
00001A50	01			1186+	DC	肚1' 1'	M5 used
00001A51	00			1187+	DC	HL1' 0'	CC
00001A52	07			1188+	DC	HL1' 7'	CC failed mask
00001A54	00000000 00000000			1189+	DS	2F	extracted PSW after test (has CC)
00001A5C	FF			1190+	DC DC	X' FF'	extracted CC, if test failed
00001A5D	E5C9E2E3 D9404040			1191+	DC DC	CL8' VISTR'	instruction name
00001A68 00001A6C	00001ACC 00001ADC			1192+ 1193+	DC DC	A(RE15) A(RE15+16)	address of v1 result
00001A6C 00001A70	00001ADC 00001AEC			1193+ 1194+	DC DC	A(RE15+16) A(RE15+32)	address of v2 source address of v3 source
00001A70 00001A74	00001AEC 00000010			1194+ 1195+	DC DC	$\begin{array}{c} A(RE15+32) \\ A(16) \end{array}$	result length
00001A74	000010 00001ACC			1195+ 1196+REA15	DC	A(RE15)	result address
00001A78	00001ACC 000000000			1190+REA13 1197+	DS	FD	
00001A80	0000000 0000000			1197+ 1198+V1015	DS DS	XL16	gap V1 output
000011100	0000000 0000000			1100 11010	D O	1210	11 oucput

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LOC	OBJECT CODE	ADDR1	ADDR2	STM						
00001A90	0000000 00000000									
				1199+	DS	FD	gap			
				1200+*	- ~	.=				
00001AA0	4110 OFFO		000010E0	1201+X15	DS	OF	land and forder			
00001AA0	4110 8EF8 E751 0000 0806		000010F8 00000000	1202+ 1203+	LA VL	R1, V1FUDGE v21, O(R1)	load v21 fudge			
	E310 5024 0014		00000000		LGF	R1, V2ADDR	load v2 source			
	E761 0000 0806		00000000		VL	v22, 0(R1)	use v21 to test decoder			
				1206+		V21, V22, 0, 1	test instruction			
00001ABC			0000000	1207+		R2, R0	extract psw			
00001AC0	5020 500C E750 5040 080E		000000C 00001A88	1208+ 1209+	ST VST	R2, CCPSW V21, V1015	to save CC save v1 output			
00001AC4			00001A00	1210+ 1210+	BR	R11	return			
00001ACC	0.12			1211+RE15	DC	0F	V1 for this test			
00001ACC				1212+	DROP	R5				
00001ACC				1213	DC	XL16' 01020304	05060708 090A0000 00000000'	$\mathbf{v1}$		
00001AD4	090A0000 00000000			1014	DC.	VI 16! 01090904	05060708 090A000C 0D0E0F10'	v2		
	01020304 05060708 090A000C 0D0E0F10			1214	DC	AL10 01020304	USUBU7U8 USUAUUUC UDUEUFIU	VZ		
OOOTAL4	OSOAGGOC ODGEGITO			1215						
				1216	VRR_A	VISTR, 0, 1, 0				
00001AF0				1217+	DS	OFD			_	
00001AF0	00001040	00001AF0		1218+	USING		base for test data and t	est rout	i ne	
00001AF0 00001AF4	00001B48 0010			1219+T16 1220+	DC DC	A(X16) H' 16'	address of test routine test number			
00001AF4				1221+	DC	X' 00'	test number			
00001AF7				1222+	DC	HL1'0'	MB used			
00001AF8				1223+	DC	HL1' 1'	M5 used			
00001AF9	00			1224+	DC	HL1' 0'	CC			
00001AFA 00001AFC				1225+ 1226+	DC	HL1' 7' 2F	CC failed mask extracted PSW after test	(has CC	`	
	FF			1227+	DS DC	X' FF'	extracted FSW after test extracted CC, if test fa		,	
	E5C9E2E3 D9404040			1228+	DC	CL8' VISTR'	instruction name	iicu		
00001B10				1229+	DC	A(RE16)	address of v1 result			
00001B14	00001B84			1230+	DC	A(RE16+16)	address of v2 source			
00001B18	00001B94			1231+	DC	A(RE16+32)	address of v3 source			
00001B1C 00001B20	00000010 00001B74			1232+ 1233+REA16	DC DC	A(16) A(RE16)	result length result address			
00001B28	0000000 00000000			1234+	DS	FD				
00001B30	0000000 00000000			1235+V1016	DS	XL16	gap V1 output			
00001B38	00000000 00000000			1000	Th C	TID	-			
00001B40	00000000 00000000			1236+	DS	FD	gap			
00001B48				1237+* 1238+X16	DS	OF				
00001B48	4110 8EF8		000010F8	1239+	LA	R1, V1FUDGE	load v21 fudge			
00001B4C	E751 0000 0806		00000000	1240+	VL	v21, 0(R1)				
00001B52	E310 5024 0014			1241+	LGF	R1, V2ADDR	load v2 source			
00001B58	E761 0000 0806		0000000	1242+	VL VI CTD	v22, 0(R1)	use v21 to test decoder			
00001B5E 00001B64	E756 0010 0C5C B98D 0020			1243+ 1244+	FDCM	V21, V22, 0, 1 R2, R0	test instruction			
00001B64	5020 500C		000000C	1244+ 1245+	ST	R2, CCPSW	extract psw to save CC			
00001B6C	E750 5040 080E		00001B30	1246+	VST	V21, V1016	save v1 output			
00001B72	07FB			1247+	BR	R11	return			
00001B74				1248+RE16	DC	0F	V1 for this test			
00001B74 00001B74	01020304 05060708			1249+ 1250	DROP DC	R5	05060708 09000000 00000000'	v.1		
000010/4	U1U2U3U4 U3U0U7U8			1230	DC	AL10 01020304	03000700 03000000 00000000	v1		

DS

DC

2F

X' FF'

extracted PSW after test (has CC)

extracted CC, if test failed

1300 +

1301 +

0000000 00000000

00001C4C

00001C54

FF

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LOC	OBJECT CODE	ADDR1	ADDR2	STM			
00001C55	E5C9E2E3 D9404040			1302+	DC	CL8' VI STR'	instruction name
00001C33	00001CC4			1303+	DC	A(RE18)	address of v1 result
00001C64	00001CD4			1304+	DC	A(RE18+16)	address of v2 source
00001C04 00001C68	00001CB4 00001CE4			1304+ 1305+	DC	A(RE18+32)	address of v3 source
00001C08	00001014			1305+ 1306+	DC		
				1300+ 1307+REA18		A(16)	result length
00001C70	00001CC4				DC	A(RE18)	result address
00001C78	00000000 00000000			1308+	DS	FD	gap V1 output
00001C80	00000000 00000000			1309+V1018	DS	XL16	VI output
00001C88	$00000000 \ 00000000$			1010	D.C.	TID	
00001C90	0000000 00000000			1310+	DS	FD	gap
00004600				1311+*	D.C.		
00001C98				1312+X18	DS	OF	
	4110 8EF8		000010F8	1313+	LA	R1, V1FUDGE	load v21 fudge
00001C9C	E751 0000 0806		00000000	1314+	VL	v21, 0(R1)	
00001CA2	E310 5024 0014		00000024	1315+	LGF	R1, V2ADDR	load v2 source
00001CA8	E761 0000 0806		00000000	1316+	VL	v22, 0(R1)	use v21 to test decoder
00001CAE	E756 0010 0C5C			1317+	VISTR	V21, V22, 0, 1	test instruction
00001CB4	B98D 0020			1318+	EPSW	R2, R0	extract psw
00001CB8	5020 500C		000000C	1319+	ST	R2, CCPSW	to save CC
00001CBC	E750 5040 080E		00001C80	1320+	VST	V21, V1018	save v1 output
00001CC2	07FB			1321+	BR	R11	return
00001CC4				1322+RE18	DC	OF	V1 for this test
00001CC4				1323+	DROP	R5	
	01020304 05060700			1324	DC		05060700 00000000 00000000' v1
00001CCC	0000000 00000000						
	01020304 05060700			1325	DC	XL16' 01020304	05060700 090A0B0C 0D0E0F10' v2
00001CDC	O9OAOBOC ODOEOF10						
				1326			
				1060			
					VRR A	VI STR. 0. 1. 0	
00001CE8				1327		VI STR, 0, 1, 0 OFD	
00001CE8 00001CE8		00001CE8		1327 1328+	DS	OFD	base for test data and test routine
00001CE8	00001D40	00001CE8		1327 1328+ 1329+	DS USING	OFD *, R5	base for test data and test routine
00001CE8 00001CE8	00001D40 0013	00001CE8		1327 1328+ 1329+ 1330+T19	DS USING DC	0FD *, R5 A(X19)	address of test routine
00001CE8 00001CE8 00001CEC	0013	00001CE8		1327 1328+ 1329+ 1330+T19 1331+	DS USING DC DC	OFD *, R5 A(X19) H' 19'	
00001CE8 00001CE8 00001CEC 00001CEE	0013 00	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+	DS USING DC DC DC	OFD *, R5 A(X19) H' 19' X' 00'	address of test routine test number
00001CE8 00001CE8 00001CEC 00001CEE 00001CEF	0013 00 00	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+	DS USING DC DC DC DC	OFD *, R5 A(X19) H' 19' X' 00' HL1' 0'	address of test routine test number M3 used
00001CE8 00001CE8 00001CEC 00001CEE 00001CEF	0013 00 00 01	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+ 1334+	DS USING DC DC DC DC DC DC	OFD *, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1'	address of test routine test number M3 used M5 used
00001CE8 00001CEC 00001CEC 00001CEF 00001CFO 00001CF0	0013 00 00 01 00	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+ 1334+ 1335+	DS USING DC DC DC DC DC DC DC	OFD *, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 1'	address of test routine test number MB used M5 used CC
00001CE8 00001CEC 00001CEC 00001CEF 00001CFO 00001CF1 00001CF2	0013 00 00 01 00 07	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1334+ 1335+ 1336+	DS USING DC DC DC DC DC DC DC DC DC	OFD *, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 1' HL1' 7'	address of test routine test number MB used M5 used CC CC failed mask
00001CE8 00001CEC 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4	0013 00 00 01 00 07 00000000 00000000	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1334+ 1335+ 1336+ 1337+	DS USING DC	OFD *, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC)
00001CE8 00001CEC 00001CEE 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC	0013 00 00 01 00 07 00000000 00000000 FF	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+ 1335+ 1336+ 1337+ 1338+	DS USING DC	OFD *, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF'	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed
00001CE8 00001CEC 00001CEE 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC	0013 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+ 1334+ 1335+ 1336+ 1337+ 1338+ 1339+	DS USING DC	0FD *, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR'	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name
00001CE8 00001CE8 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD	0013 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00001D6C	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+ 1334+ 1335+ 1336+ 1337+ 1338+ 1339+ 1340+	DS USING DC	0FD *, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result
00001CE8 00001CEC 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD 00001D08 00001D0C	0013 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00001D6C 00001D7C	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+ 1334+ 1335+ 1336+ 1337+ 1338+ 1339+ 1340+ 1341+	DS USING DC	*, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source
00001CE8 00001CEC 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD 00001D08 00001D0C 00001D10	0013 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00001D6C 00001D7C 00001D8C	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1334+ 1335+ 1336+ 1337+ 1338+ 1339+ 1340+ 1341+ 1342+	DS USING DC	0FD *, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16) A(RE19+32)	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source
00001CE8 00001CEC 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD 00001D08 00001D0C 00001D10	0013 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00001D6C 00001D7C 00001D8C 00000010	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1334+ 1335+ 1336+ 1337+ 1338+ 1340+ 1341+ 1342+ 1343+	DS USING DC	0FD *, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16) A(RE19+32) A(16)	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length
00001CE8 00001CES 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD 00001D08 00001D0C 00001D10 00001D14 00001D18	0013 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00001D6C 00001D8C 0000010 00001D6C	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1334+ 1335+ 1336+ 1337+ 1338+ 1340+ 1341+ 1342+ 1342+ 1343+ 1344+REA19	DS USING DC	0FD *, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16) A(RE19+32) A(16) A(RE19)	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address
00001CE8 00001CEC 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD 00001D08 00001D0C 00001D10 00001D14 00001D18 00001D20	0013 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00001D6C 00001D8C 0000010 00001D6C 00001D6C 00000000 00000000	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+ 1335+ 1336+ 1337+ 1338+ 1340+ 1341+ 1342+ 1342+ 1343+ 1344+REA19 1345+	DS USING DC	*, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16) A(RE19+32) A(16) A(RE19) FD	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address
00001CE8 00001CE8 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD 00001D08 00001D0C 00001D10 00001D18 00001D18 00001D20 00001D20	0013 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00001D6C 00001D7C 00001D8C 00001D6C 00001D6C 00000000 00000000 00000000 00000000	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1334+ 1335+ 1336+ 1337+ 1338+ 1340+ 1341+ 1342+ 1342+ 1343+ 1344+REA19	DS USING DC	0FD *, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16) A(RE19+32) A(16) A(RE19)	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length
00001CE8 00001CE8 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD 00001D08 00001D0C 00001D10 00001D18 00001D18 00001D20 00001D20 00001D30	0013 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00001D6C 00001D6C 00001D6C 00001D6C 00001D6C 00000000 00000000 00000000 00000000 00000000	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1334+ 1335+ 1336+ 1337+ 1338+ 1339+ 1340+ 1341+ 1342+ 1343+ 1344+REA19 1345+ 1346+V1019	DS USING DC	*, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16) A(RE19+32) A(16) A(RE19) FD XL16	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output
00001CE8 00001CE8 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD 00001D08 00001D0C 00001D10 00001D18 00001D18 00001D20 00001D20	0013 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00001D6C 00001D7C 00001D8C 00001D6C 00001D6C 00000000 00000000 00000000 00000000	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+ 1334+ 1335+ 1336+ 1339+ 1340+ 1341+ 1342+ 1343+ 1344+REA19 1345+ 1346+V1019	DS USING DC	*, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16) A(RE19+32) A(16) A(RE19) FD	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address
00001CE8 00001CEC 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF2 00001CFC 00001CFD 00001D0S 00001D0C 00001D10 00001D14 00001D18 00001D20 00001D20 00001D30 00001D30	0013 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00001D6C 00001D6C 00001D6C 00001D6C 00001D6C 00000000 00000000 00000000 00000000 00000000	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1334+ 1335+ 1336+ 1337+ 1338+ 1340+ 1341+ 1342+ 1343+ 1344+REA19 1345+ 1346+V1019	DS USING DC	*, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16) A(RE19+32) A(16) A(RE19) FD XL16 FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output
00001CE8 00001CEC 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD 00001D08 00001D0C 00001D10 00001D14 00001D18 00001D20 00001D20 00001D30 00001D30	0013 00 01 00 07 00000000 000000000 FF E5C9E2E3 D9404040 00001D6C 00001D7C 00001D8C 0000010 00001D6C 00000000 00000000 00000000 00000000 00000000	00001CE8	000010E9	1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+ 1334+ 1335+ 1336+ 1339+ 1340+ 1341+ 1342+ 1343+ 1344+REA19 1345+ 1346+V1019	DS USING DC	*, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16) A(RE19+32) A(16) A(RE19) FD XL16 FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap
00001CE8 00001CE8 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD 00001D08 00001D0C 00001D10 00001D14 00001D18 00001D20 00001D28 00001D30 00001D38	0013 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00001D6C 00001D7C 00001D8C 00001D6C 00001D6C 0000000 00000000 00000000 00000000 00000000	00001CE8	000010F8	1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+ 1335+ 1336+ 1337+ 1338+ 1340+ 1341+ 1342+ 1343+ 1344+REA19 1345+ 1346+V1019 1347+ 1348+* 1349+X19 1350+	DS USING DC	*, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16) A(RE19+32) A(16) A(RE19) FD XL16 FD OF R1, V1FUDGE	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output
00001CE8 00001CE8 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD 00001D0S 00001D0C 00001D10 00001D14 00001D18 00001D20 00001D20 00001D30 00001D30 00001D40 00001D40 00001D40	0013 00 01 00 07 00000000 000000000 FF E5C9E2E3 D9404040 00001D6C 00001D7C 00001D6C 000001D6C 0000000 00000000 0000000 00000000 00000000	00001CE8	00000000	1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+ 1335+ 1336+ 1337+ 1338+ 1340+ 1341+ 1342+ 1342+ 1343+ 1344+REA19 1345+ 1346+V1019 1347+ 1348+* 1349+X19 1350+ 1351+	DS USING DC	*, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16) A(RE19+32) A(16) A(RE19) FD XL16 FD OF R1, V1FUDGE v21, O(R1)	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge
00001CE8 00001CE8 00001CEC 00001CEF 00001CF0 00001CF1 00001CF2 00001CF4 00001CFC 00001CFD 00001D08 00001D0C 00001D10 00001D14 00001D18 00001D20 00001D28 00001D30 00001D38	0013 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00001D6C 00001D7C 00001D8C 00001D6C 00001D6C 0000000 00000000 00000000 00000000 00000000	00001CE8		1327 1328+ 1329+ 1330+T19 1331+ 1332+ 1333+ 1335+ 1336+ 1337+ 1338+ 1340+ 1341+ 1342+ 1343+ 1344+REA19 1345+ 1346+V1019 1347+ 1348+* 1349+X19 1350+	DS USING DC	*, R5 A(X19) H' 19' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE19) A(RE19+16) A(RE19+32) A(16) A(RE19) FD XL16 FD OF R1, V1FUDGE	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap

ASMA Ver. 0.7.0 zvector-e7-06-Find (Zvector E7 VRR-a instruction) 31 L_OC **OBJECT CODE** ADDR1 ADDR2 **STM** E756 0010 0C5C 00001D56 1354+ VISTR V21, V22, 0, 1 test instruction EPSW R2, R0 00001D5C B98D 0020 1355+ extract psw 00001D60 5020 500C 000000C 1356+ ST R2, CCPSW to save CC E750 5040 080E 00001D28 1357+ **VST** V21, V1019 save v1 output 00001D64 1358+ 00001D6A **07FB** BR **R11** return 1359+RE19 0F 00001D6C DC V1 for this test **R5** 00001D6C 1360 +**DROP** 00001D6C 01020304 05060000 1361 DC XL16' 01020304 05060000 00000000 00000000' v10000000 00000000 00001D74 00001D7C 01020304 05060008 1362 DC XL16' 01020304 05060008 090A0B0C 0D0E0F10' v200001D84 090A0B0C 0D0E0F10 1363 1364 VRR_A VISTR, 0, 1, 0 1365+ 00001D90 DS **OFD** 00001D90 00001D90 1366+ USING *, R5 base for test data and test routine A(X20)00001DE8 1367+T20 00001D90 DC address of test routine 0014 1368+ DC H' 20' 00001D94 test number 00001D96 1369+ DC X' 00' 00 1370+ HL1'0' MB used 00001D97 00 DC HL1' 1' DC 00001D98 1371+ 01 M5 used 00001D99 00 1372+ DC HL1' 0' CC 1373+ DC HL1'7' CC failed mask 00001D9A 07 00001D9C 0000000 00000000 1374+ DS 2F extracted PSW after test (has CC) DC X' FF' extracted CC, if test failed 00001DA4 FF 1375 +E5C9E2E3 D9404040 1376+ DC CL8' VISTR' 00001DA5 instruction name 00001DB0 00001E14 1377+ DC A(RE20) address of v1 result 00001DB4 1378+ A(RE20+16)address of v2 source 00001E24 DC 00001DB8 00001E34 1379+ DC A(RE20+32)address of v3 source 1380 +DC result length 00001DBC 00000010 A(16) 1381+REA20 A(RE20) 00001DC0 00001E14 DC result address 0000000 00000000 DS 00001DC8 1382+ FD gap V1 output 00001DD0 0000000 00000000 1383+V1020 DS **XL16** 00001DD8 0000000 00000000 0000000 00000000 1384+ DS FD 00001DE0 gap 1385+* 1386+X20 DS 0F 00001DE8 00001DE8 4110 8EF8 000010F8 1387+ LA R1, V1FUDGE load v21 fudge 00001DEC E751 0000 0806 0000000 1388+ VL v21, 0(R1)E310 5024 0014 1389+ R1, V2ADDR load v2 source 00001DF2 00000024 LGF E761 0000 0806 v22, 0(R1)00001DF8 1390+ VL use v21 to test decoder 00000000 VISTR V21, V22, 0, 1 00001DFE E756 0010 0C5C 1391+ test instruction EPSW R2, R0 00001E04 B98D 0020 1392+ extract psw 00001E08 5020 500C 000000C 1393+ ST R2, CCPSW to save CC E750 5040 080E 1394+ **VST** V21, V1020 00001E0C 00001DD0 save v1 output 1395+ R11 00001E12 07FB BR return 1396+RE20 DC 00001E14 0F V1 for this test **R5** 00001E14 1397 +DROP 01020304 05000000 1398 XL16' 01020304 05000000 00000000 00000000' 00001E14 DC v100001E1C 0000000 00000000 1399 DC 00001E24 01020304 05000708 XL16' 01020304 05000708 090A0B0C 0D0E0F10' v2**00001E2C 090A0B0C 0D0E0F10** 1400 VRR_A VISTR, 0, 1, 0 1401 00001E38 1402+ DS **OFD** USING *, R5 00001E38 00001E38 1403+ base for test data and test routine 00001E90 00001E38 DC 1404+T21 A(X21)address of test routine

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LOC	OBJECT CODE	ADDR1	ADDR2	STMI			
00001E3C	0015			1405+	DC	Н' 21'	test number
00001E3E	00			1406+	DC	X' 00'	
00001E3F	00			1407+	DC	HL1' 0'	MB used
00001E40	01			1408+	DC	HL1' 1'	M5 used
00001E41	00			1409+	DC	HL1' 0'	CC
00001E42				1410+	DC	HL1' 7'	CC failed mask
00001E44	0000000 00000000			1411+	DS	2F	extracted PSW after test (has CC)
00001E4C	FF			1412+	DC	X' FF'	extracted CC, if test failed
00001E4D	E5C9E2E3 D9404040			1413+	DC	CL8' VISTR'	instruction name
00001E58	00001EBC			1414+	DC	A(RE21)	address of v1 result
00001E5C	00001ECC			1415+	DC	A(RE21+16)	address of v2 source
00001E60	00001EDC			1416+	DC	A(RE21+32)	address of v3 source
00001E64	0000010			1417+	DC	A(16)	result length
00001E68	00001EBC			1418+REA21	DC	A(RE21)	result address
00001E70	00000000 00000000			1419+	DS	FD	gap V1 output
00001E78	00000000 00000000			1420+V1021	DS	XL16	V1 output
00001E80	00000000 00000000						
00001E88	00000000 00000000			1421+	DS	FD	gap
000047700				1422+*	~~		
00001E90				1423+X21	DS	0F	
00001E90	4110 8EF8		000010F8	1424+	LA	R1, V1FUDGE	load v21 fudge
	E751 0000 0806		00000000	1425+	VL	v21, 0(R1)	
00001E9A	E310 5024 0014		00000024	1426+	LGF	R1, V2ADDR	load v2 source
00001EA0	E761 0000 0806		00000000	1427+	VL	v22, 0(R1)	use v21 to test decoder
00001EA6	E756 0010 0C5C			1428+	VISTR	V21, V22, 0, 1	test instruction
00001EAC	B98D 0020		0000000	1429+	EPSW	R2, R0	extract psw
00001EB0	5020 500C		000000C	1430+	ST	R2, CCPSW	to save CC
00001EB4	E750 5040 080E		00001E78	1431+	VST	V21, V1021	save v1 output
00001EBA	07FB			1432+	BR	R11	return
00001EBC				1433+RE21	DC	OF	V1 for this test
00001EBC	01020204 0000000			1434+	DROP	R5	0000000 0000000 000000001
00001EBC	01020304 00000000			1435	DC	AL10 U1U2U3U4	00000000 00000000 00000000' v1
	00000000 00000000 01020304 00060708			1436	DC	VI 16! 01090904	00060708 090A0B0C 0D0E0F10' v2
	090A0B0C 0D0E0F10			1430	DC	AL10 01020304	UUUUU7U8 USUAUBUC UDUEUFIU V2
00001ED4	USUAUBUC UDUEUFIU			1437			
				1438	V/DD A	VI STR, 0, 1, 0	
00001EE0				1439+	DS	0FD	
00001EE0		00001EE0		1440+	USING		base for test data and test routine
00001EE0	00001F38	OOOOTLLO		1441+T22	DC	A(X22)	address of test routine
00001EE4	0016			1442+	DC	H' 22'	test number
00001EE4	00			1443+	DC	X' 00'	cese number
00001EE7	00			1444+	DC	HL1' 0'	MB used
00001EE8	01			1445+	DC	HL1' 1'	M5 used
	00			1446+	DC	HL1' 0'	CC
	07			1447+	DC	HL1' 7'	CC failed mask
00001EEC	00000000 00000000			1448+	DS	2F	extracted PSW after test (has CC)
00001EF4	FF			1449+	DC	X' FF'	extracted CC, if test failed
00001EF5	E5C9E2E3 D9404040			1450+	DC	CL8' VISTR'	instruction name
00001F00	00001F64			1451+	DC	A(RE22)	address of v1 result
00001F04	00001F74			1452+	DC	A(RE22+16)	address of v2 source
00001F08	00001F84			1453+	DC	A(RE22+32)	address of v3 source
00001F0C	0000010			1454+	DC	A(16)	result length
00001F10	00001F64			1455+REA22	DC	A(RE22)	result address
00001F18	0000000 00000000			1456+	DS	FD	
00001F20	0000000 00000000			1457+V1022	DS	XL16	gap V1 output
							•

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LOC	OBJECT CODE	ADDR1	ADDR2	STMT						
00001F28	0000000 00000000									
				1458+	DS	FD	gap			
00004700				1459+*	D.C.					
00001F38	4110 OFFO		000010E0	1460+X22	DS	OF	land wolf forder			
00001F38	4110 8EF8 E751 0000 0806		000010F8 00000000	1461+ 1462+	LA VL	R1, V1FUDGE v21, O(R1)	load v21 fudge			
	E310 5024 0014		00000000		LGF	R1, V2ADDR	load v2 source			
	E761 0000 0806		00000000		VL	v22, 0(R1)	use v21 to test decoder			
	E756 0010 0C5C			1465+		V21, V22, 0, 1	test instruction	ı		
00001F54				1466+		R2, RO	extract psw			
00001F58	5020 500C		000000C		ST	R2, CCPSW	to save CC			
00001F5C 00001F62	E750 5040 080E 07FB		00001F20	1468+ 1469+	VST BR	V21, V1022 R11	save v1 output return			
00001F62 00001F64	07ГВ			1409+ 1470+RE22	DC DC	OF	V1 for this test			
00001F64				1471+	DROP	R5	VI 101 this test			
00001F64	01020300 00000000			1472	DC		0000000 00000000 00000000'	$\mathbf{v1}$		
	00000000 00000000							_		
	01020300 05060708			1473	DC	XL16' 01020300	05060708 090A0B0C 0D0E0F10'	$\mathbf{v2}$		
00001F7C	O9OAOBOC ODOEOF10			1474						
				1475	VRR A	VI STR, 0, 1, 0				
00001F88				1476+	DS DS	0FD				
00001F88		00001F88		1477+	USING		base for test data and t	est rout	i ne	
00001F88	00001FE0			1478+T23	DC	A(X23)	address of test routine			
00001F8C				1479+	DC	H' 23'	test number			
00001F8E				1480+	DC	X' 00'	M) wood			
00001F8F 00001F90				1481+ 1482+	DC DC	HL1' 0' HL1' 1'	M3 used M5 used			
				1483+	DC	HL1' 0'	CC			
00001F92				1484+	DC	HL1' 7'	CC failed mask			
00001F94				1485+	DS	2F	extracted PSW after test)	
00001F9C				1486+	DC	X' FF'	extracted CC, if test fa	i l ed		
00001F9D 00001FA8	E5C9E2E3 D9404040			1487+ 1488+	DC DC	CL8' VISTR'	instruction name			
00001FA8	0000200C 0000201C			1489+	DC DC	A(RE23) A(RE23+16)	address of v1 result address of v2 source			
00001FB0	0000201C			1490+	DC	A(RE23+32)	address of v3 source			
00001FB4	00000010			1491+	DC	A(16)	result length			
00001FB8	0000200C			1492+REA23	DC	A(RE23)	result address			
00001FC0	00000000 00000000			1493+	DS	FD	gap V1 output			
00001FC8 00001FD0	0000000 00000000 0000000 00000000			1494+V1023	DS	XL16	vi output			
00001FD0	0000000 0000000			1495+	DS	FD	gap			
000011100				1496+*			8r			
00001FE0				1497+X23	DS	OF				
00001FE0	4110 8EF8		000010F8	1498+	LA	R1, V1FUDGE	load v21 fudge			
00001FE4	E751 0000 0806		00000000	1499+	VL LCE	v21, 0(R1)	lood vo sames			
00001FEA 00001FF0	E310 5024 0014 E761 0000 0806		00000024 00000000	1500+ 1501+	LGF VL	R1, V2ADDR v22, O(R1)	load v2 source use v21 to test decoder			
	E756 0010 0C5C		0000000	1502+		V22, 0(R1) V21, V22, 0, 1	test instruction			
00001FFC	B98D 0020			1503+	EPSW	R2, R0	extract psw			
00002000	5020 500C		000000C	1504+	ST	R2, CCPSW	to save CC			
00002004	E750 5040 080E		00001FC8	1505+	VST	V21, V1023	save v1 output			
0000200A 0000200C	07FB			1506+ 1507+RE23	BR DC	R11 OF	return V1 for this test			
0000200C				1507+RE25 1508+	DROP	R5	vi for this test			
	01020000 00000000			1509	DC		0000000 00000000 00000000'	v1		

DS

DC

2F

X' FF'

extracted PSW after test (has CC)

extracted CC, if test failed

1559 +

1560 +

000020E4

000020EC

FF

	OD LECT CODE	,					12 rep 2023 14. 20. 10 rage	30
LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
				1586 *hal fwor	d			
00000100				1587	VRR_A	VISTR, 1, 1, 3		
00002180		00000100		1588+	DS	OFD	have Compared data and tract months	
00002180	000001B0	00002180		1589+	USING		base for test data and test routine	
00002180 00002184	000021D8			1590+T26	DC DC	A(X26)	address of test routine	
00002184	001A 00			1591+ 1592+	DC DC	H' 26' X' 00'	test number	
00002180	01			1593+	DC DC	HL1' 1'	MB used	
00002187	01			1594+	DC	HL1' 1'	M5 used	
00002189	03			1595+	DC	HL1' 3'	CC	
0000218A	0E			1596+	DC	HL1' 14'	CC failed mask	
0000218C	0000000 00000000			1597+	DS	2F	extracted PSW after test (has CC)	
00002194	FF			1598+	DC	X' FF'	extracted CC, if test failed	
00002195	E5C9E2E3 D9404040			1599+	DC	CL8' VI STR'	instruction name	
000021A0	00002204			1600+	DC	A(RE26)	address of v1 result	
000021A4	00002214			1601+	DC	A(RE26+16)	address of v2 source	
000021A8	00002224			1602+	DC	A(RE26+32)	address of v3 source	
000021AC	00000010			1603+	DC	A(16)	result length	
000021B0	00002204			1604+REA26	DC	A(RE26)	result address	
000021B8	00000000 00000000			1605+	DS	FD VI 10	gap V1 output	
000021C0 000021C8	$\begin{array}{cccc} 00000000 & 00000000 \\ 00000000 & 00000000$			1606+V1026	DS	XL16	vi output	
000021C8	0000000 0000000			1607+	DS	FD	dan	
000021D0	0000000 0000000			1608+*	טע	T D	gap	
000021D8				1609+X26	DS	0F		
000021D8	4110 8EF8		000010F8	1610+	LA	R1, V1FUDGE	load v21 fudge	
000021DC	E751 0000 0806		00000000	1611+	VL	v21, 0(R1)		
000021E2	E310 5024 0014		00000024	1612+	LGF	R1, V2ÀDDR	load v2 source	
000021E8	E761 0000 0806		00000000	1613+	VL	v22, 0(R1)	use v21 to test decoder	
000021EE	E756 0010 1C5C			1614+	VISTR	V21, V22, 1, 1	test instruction	
000021F4	B98D 0020			1615+		R2, R0	extract psw	
000021F8	5020 500C		000000C	1616+	ST	R2, CCPSW	to save CC	
000021FC	E750 5040 080E		000021C0	1617+	VST	V21, V1026	save v1 output	
00002202	07FB			1618+ 1619+RE26	BR DC	R11	return	
00002204 00002204				1619+KE26 1620+		OF R5	V1 for this test	
00002204	8888888 77777777			1621	DROP		7777777 66666666 55555555' v2	
00002204 0000220C	66666666 55555555			1021	ьс	AL10 00000000	7777777 0000000 33333333	
00002214	8888888 7777777			1622	DC	XI.16' 88888888	7777777 66666666 55555555' v2	
0000221C	6666666 5555555							
				1623				
				1624		VISTR, 1, 1, 0		
00002228				1625+	DS	OFD		
00002228		00002228		1626+	USING		base for test data and test routine	
00002228	00002280			1627+T27	DC	A(X27)	address of test routine	
0000222C	001B			1628+	DC	H' 27'	test number	
0000222E	00			1629+	DC	X' 00'	ND J	
0000222F	01			1630+ 1631+	DC DC	HL1' 1'	MB used	
00002230 00002231	01 00			1631+ 1632+	DC DC	HL1' 1' HL1' 0'	M5 used CC	
00002231	07			1632+ 1633+	DC DC	HL1'7'	CC failed mask	
00002232	00000000 00000000			1634+	DS DS	2F	extracted PSW after test (has CC)	
00002234 0000223C	FF			1635+	DC DC	X' FF'	extracted CC, if test failed	
0000223D	E5C9E2E3 D9404040			1636+	DC	CL8' VISTR'	instruction name	
00002248	000022AC			1637+	DC	A(RE27)	address of v1 result	
0000224C	000022BC			1638+	DC	A(RE27+16)	address of v2 source	
						,		

ASMA Ver	0. 7. 0 zvector- e7-0)6-Find (Zv	ector E7 V	KK-a instructi	on)		12 Feb 2025 14: 26: 16 Page	37
LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
00002250	000022CC			1639+	DC	A(RE27+32)	address of v3 source	
00002254				1640+	DC	A(16)	result length	
00002258	000022AC			1641+REA27	DC	A(RE27)	result address	
00002260	0000000 00000000			1642+	DS	FD	gap	
00002268	0000000 00000000			1643+V1027	DS	XL16	gap V1 output	
00002270	0000000 00000000						•	
00002278	0000000 00000000			1644+	DS	FD	gap	
				1645+*				
00002280				1646+X27	DS	OF		
00002280	4110 8EF8		000010F8	1647+	LA	R1, V1FUDGE	load v21 fudge	
00002284			00000000	1648+	VL	v21, 0(R1)	G	
0000228A			00000024	1649+	LGF	R1, V2ADDR	load v2 source	
00002290			00000000	1650+	VL	v22, 0(R1)	use v21 to test decoder	
00002296				1651+	VISTR	V21, V22, 1, 1	test instruction	
0000229C				1652+	EPSW	R2, R0	extract psw	
000022A0			000000C	1653+	ST	R2, CCPSW	to save CC	
000022A4	E750 5040 080E		00002268	1654+	VST	V21, V1027	save v1 output	
000022AA	07FB			1655+	BR	R11	return	
000022AC				1656+RE27	DC	OF	V1 for this test	
000022AC				1657+	DROP	R5		
000022AC				1658	DC	XL16' 88888888	7777777 66666666 55550000' v2	
000022B4								
000022BC				1659	DC	XL16' 88888888	7777777 66666666 55550000' v2	
000022C4	66666666 55550000							
				1660				
				1661		VISTR, 1, 1, 0		
000022D0				1662+	DS	OFD		
000022D0		000022D0		1663+	USING	*, R 5	base for test data and test routine	
000022D0 000022D0		000022D0		1663+ 1664+T28	USI NG DC	*, R5 A(X28)	address of test routine	
000022D0 000022D0 000022D4	001C	000022D0		1663+ 1664+T28 1665+	USING DC DC	*, R5 A(X28) H' 28'		
000022D0 000022D0 000022D4 000022D6	001C 00	000022D0		1663+ 1664+T28 1665+ 1666+	USING DC DC DC	*, R5 A(X28) H' 28' X' 00'	address of test routine test number	
000022D0 000022D0 000022D4 000022D6 000022D7	001C 00 01	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+	USING DC DC DC DC	*, R5 A(X28) H' 28' X' 00' HL1' 1'	address of test routine test number MB used	
000022D0 000022D4 000022D6 000022D7 000022D8	001C 00 01 01	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+	USING DC DC DC DC DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1'	address of test routine test number MB used M5 used	
000022D0 000022D4 000022D6 000022D7 000022D8 000022D9	001C 00 01 01 00	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+	USING DC DC DC DC DC DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 0'	address of test routine test number MB used M5 used CC	
000022D0 000022D4 000022D6 000022D7 000022D8 000022D9 000022DA	001C 00 01 01 00 07	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+	USING DC DC DC DC DC DC DC DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 0' HL1' 7'	address of test routine test number MB used M5 used CC CC failed mask	
000022D0 000022D4 000022D6 000022D7 000022D8 000022D9 000022DA 000022DC	001C 00 01 01 00 07 00000000 00000000	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 0' HL1' 7' 2F	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC)	
000022D0 000022D0 000022D4 000022D6 000022D7 000022D9 000022DA 000022DC 000022E4	001C 00 01 01 00 07 00000000 00000000 FF	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF'	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed	
000022D0 000022D4 000022D6 000022D7 000022D8 000022DA 000022DA 000022E4 000022E4	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR'	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name	
000022D0 000022D4 000022D6 000022D7 000022D8 000022D9 000022DA 000022DC 000022E4 000022E5 000022F0	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result	
000022D0 000022D4 000022D6 000022D7 000022D8 000022D9 000022DC 000022E4 000022E5 000022F0	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002364	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source	
000022D0 000022D4 000022D6 000022D7 000022D9 000022DA 000022DC 000022E4 000022E5 000022F0 000022F4	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002364 00002374	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source	
000022D0 000022D4 000022D6 000022D7 000022D8 000022D9 000022DA 000022E4 000022E4 000022F0 000022F4 000022F8	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002364 00002374 00000010	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32) A(16)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length	
000022D0 000022D0 000022D4 000022D7 000022D8 000022DA 000022DA 000022E4 000022E4 000022F4 000022F4 000022F4 000022F6 000022FC	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002364 00002374 00000010 00002354	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+ 1678+REA28	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+32) A(RE28+32) A(16) A(RE28)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address	
000022D0 000022D4 000022D6 000022D7 000022D8 000022DA 000022DA 000022E4 000022E4 000022F0 000022F4 000022F8 000022FC 00002300 00002308	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002374 00000010 00002354 00000000 00000000	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+ 1678+REA28 1679+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32) A(16) A(RE28) FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address	
000022D0 000022D4 000022D6 000022D7 000022D8 000022DA 000022DC 000022E4 000022E5 000022F0 000022F4 000022FC 000022FC 00002300 00002308 00002310	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002354 00000010 00002354 00000000 00000000	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+ 1678+REA28	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+32) A(RE28+32) A(16) A(RE28)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length	
000022D0 000022D4 000022D6 000022D7 000022D8 000022D9 000022DC 000022E4 000022E5 000022F0 000022F4 000022F0 00002300 00002310 00002318	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002354 00002354 00000010 00002354 00000000 00000000 00000000 00000000	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+ 1678+REA28 1679+ 1680+V1028	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32) A(16) A(RE28) FD XL16	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output	
000022D0 000022D4 000022D6 000022D7 000022D8 000022DA 000022DC 000022E4 000022E5 000022F0 000022F4 000022FC 000022FC 00002300 00002308 00002310	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002354 00002354 00000010 00002354 00000000 00000000 00000000 00000000	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+ 1678+REA28 1679+ 1680+V1028	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32) A(16) A(RE28) FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address	
000022D0 000022D0 000022D4 000022D7 000022D8 000022D9 000022DA 000022E4 000022E4 000022F4 000022F4 000022FC 00002300 00002310 00002310 00002320	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002354 00002354 00000010 00002354 00000000 00000000 00000000 00000000	000022D0		1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+ 1678+REA28 1679+ 1680+V1028	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32) A(16) A(RE28) FD XL16 FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output	
000022D0 000022D4 000022D6 000022D7 000022D8 000022DA 000022DA 000022E4 000022E4 000022F4 000022F4 000022F4 000022FC 00002300 00002308 00002318 00002328	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002354 000002354 00000000 00000000 00000000 00000000 00000000	000022D0	000010F8	1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1673+ 1674+ 1675+ 1676+ 1677+ 1678+REA28 1679+ 1680+V1028	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32) A(16) A(RE28) FD XL16 FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap	
000022D0 000022D4 000022D6 000022D7 000022D8 000022DA 000022DA 000022E4 000022E5 000022F4 000022F4 000022FC 000023C0 00002308 00002310 00002328 00002328	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002354 000002354 00000000 00000000 00000000 00000000 00000000	000022D0	000010F8 00000000	1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+ 1678+REA28 1679+ 1680+V1028	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32) A(16) A(RE28) FD XL16 FD OF R1, V1FUDGE	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output	
000022D0 000022D4 000022D6 000022D7 000022D8 000022DA 000022DA 000022E4 000022E5 000022F0 000022F0 000022FC 000023C0 00002310 00002328 00002328 00002328 00002328	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0002354 00002354 00002354 00000010 00002354 00000000 00000000 00000000 00000000 00000000	000022D0	00000000	1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+ 1678+REA28 1679+ 1680+V1028 1681+ 1682+* 1683+X28 1684+ 1685+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32) A(16) A(RE28) FD XL16 FD OF R1, V1FUDGE v21, O(R1)	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge	
000022D0 000022D4 000022D6 000022D7 000022D8 000022DA 000022DC 000022E4 000022E5 000022F0 000022FC 000022FC 00002300 00002310 00002310 00002328 00002328 00002328 0000232C 00002332	001C 00 01 01 00 07 00000000 000000000 FF E5C9E2E3 D9404040 00002354 00002354 000002354 00000010 00002354 00000000 00000000 00000000 00000000 00000000	000022D0	00000000 00000024	1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+ 1678+REA28 1679+ 1680+V1028 1681+ 1682+* 1683+X28 1684+ 1685+ 1686+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 0' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32) A(16) A(RE28) FD XL16 FD OF R1, V1FUDGE v21, O(R1) R1, V2ADDR	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge load v2 source	
000022D0 000022D4 000022D6 000022D7 000022D8 000022DC 000022DC 000022E4 000022E5 000022F0 000022F0 000022F0 00002300 00002300 00002310 00002310 00002320 00002320 00002328 00002328 00002332 00002332	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002354 000002354 00000010 00002354 00000000 00000000 00000000 00000000 00000000	000022D0	00000000	1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+ 1680+V1028 1681+ 1682+* 1683+X28 1684+ 1685+ 1686+ 1687+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 0' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32) A(16) A(RE28) FD XL16 FD OF R1, V1FUDGE v21, O(R1) R1, V2ADDR v22, O(R1)	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge load v2 source use v21 to test decoder	
000022D0 000022D4 000022D6 000022D7 000022D8 000022DA 000022DC 000022E4 000022E5 000022F0 000022F4 000022F4 000022F6 00002308 00002310 00002310 00002320 00002320 00002320 00002328 00002328 00002332 00002338 00002338	001C 00 01 01 00 07 00000000 000000000 FF E5C9E2E3 D9404040 00002354 00002364 00002374 00000010 00002354 00000000 00000000 00000000 00000000 00000000	000022D0	00000000 00000024	1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+ 1680+V1028 1681+ 1682+* 1683+X28 1684+ 1685+ 1686+ 1687+ 1688+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 0' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32) A(16) A(RE28) FD XL16 FD OF R1, V1FUDGE v21, O(R1) R1, V2ADDR v22, O(R1) V21, V22, 1, 1	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge load v2 source use v21 to test decoder test instruction	
000022D0 000022D4 000022D6 000022D7 000022D8 000022DC 000022DC 000022E4 000022E5 000022F0 000022F0 000022F0 00002300 00002300 00002310 00002310 00002320 00002320 00002328 00002328 00002332 00002332	001C 00 01 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 00002354 00002354 000002354 00000010 00002354 00000000 00000000 00000000 00000000 00000000	000022D0	00000000 00000024	1663+ 1664+T28 1665+ 1666+ 1667+ 1668+ 1669+ 1670+ 1671+ 1672+ 1673+ 1674+ 1675+ 1676+ 1677+ 1680+V1028 1681+ 1682+* 1683+X28 1684+ 1685+ 1686+ 1687+	USING DC	*, R5 A(X28) H' 28' X' 00' HL1' 1' HL1' 1' HL1' 0' HL1' 7' 2F X' FF' CL8' VI STR' A(RE28) A(RE28+16) A(RE28+32) A(16) A(RE28) FD XL16 FD OF R1, V1FUDGE v21, O(R1) R1, V2ADDR v22, O(R1)	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge load v2 source use v21 to test decoder	

ASMA Ver.	0. 7. 0 zvector-e7-0	6-Find (Zv	ector E7 V	RR-a instructi	on)		12 Feb 2025 14: 26: 16 Page 38
LOC	OBJECT CODE	ADDR1	ADDR2	STMF			
0000234C 00002352	E750 5040 080E 07FB		00002310	1691+ 1692+	VST BR	V21, V1028 R11	save v1 output return
00002354 00002354				1693+RE28 1694+	DC DROP	OF R5	V1 for this test
00002354	8888888 77777777			1695	DKOP DC		7777777 66666666 00000000' v2
0000235C	66666666 00000000			1696	DC		
	8888888 7777777 6666666 00005555				ЪС	VIIO 00000000	7777777 66666666 00005555' v2
				1697 1698	VDD A	VI STR, 1, 1, 0	
00002378				1699+	DS	OFD	
00002378	00000000	00002378		1700+	USING		base for test data and test routine
00002378 0000237C	000023D0 001D			1701+T29 1702+	DC DC	A(X29) H' 29'	address of test routine test number
0000237E	00			1703+	DC	X' 00'	
0000237F 00002380	01 01			1704+ 1705+	DC DC	HL1' 1' HL1' 1'	MB used M5 used
00002381	00			1706+	DC	HL1' 0'	CC
00002382	07			1707+ 1708+	DC	Ш1' 7'	CC failed mask
00002384 0000238C	00000000 00000000 FF			1708+ 1709+	DS DC	2F X' FF'	extracted PSW after test (has CC) extracted CC, if test failed
0000238D	E5C9E2E3 D9404040			1710 +	DC	CL8' VISTR'	instruction name
00002398 0000239C	000023FC 0000240C			1711+ 1712+	DC DC	A(RE29) A(RE29+16)	address of v1 result address of v2 source
0000239C	0000240C 0000241C			1713+	DC DC	A(RE29+32)	address of v2 source
000023A4				1714+	DC	A(16)	result length
000023A8 000023B0	000023FC 0000000 00000000			1715+REA29 1716+	DC DS	A(RE29) FD	result address gap
000023B8	0000000 00000000			1717+V1029	DS	XL16	V1 output
000023C0 000023C8	00000000 00000000 0000000 00000000			1718+	DS	FD	gan
	0000000 0000000			1719+*			gap
000023D0	4110 OFFO		000010E0	1720+X29	DS	OF	land wat forder
000023D0 000023D4	4110 8EF8 E751 0000 0806		000010F8 00000000		LA VL	R1, V1FUDGE v21, O(R1)	load v21 fudge
000023DA	E310 5024 0014		00000024	1723+	LGF	R1, V2ADDR	load v2 source
000023E0 000023E6	E761 0000 0806 E756 0010 1C5C		00000000	1724+ 1725+	VL VISTR	v22, 0(R1) V21, V22, 1, 1	use v21 to test decoder test instruction
000023EC	B98D 0020			1726+	EPSW	R2, R0	extract psw
000023F0 000023F4	5020 500C E750 5040 080E		0000000C 000023B8	1727+ 1728+	ST VST	R2, CCPSW	to save CC
000023FA	07FB		UUUUZSDO	1729+	BR	V21, V1029 R11	save v1 output return
000023FC				1730+RE29	DC	0F	V1 for this test
000023FC 000023FC	8888888 7777777			1731+ 1732	DROP DC	R5 XL16' 88888888	7777777 66660000 00000000' v2
00002404	66660000 00000000						
0000240C 00002414	8888888 7777777 66660000 5555555			1733	DC	XL16' 88888888	7777777 66660000 55555555' v2
00006414	00000000 33333333			1734			
00000400				1735		VISTR, 1, 1, 0	
00002420 00002420		00002420		1736+ 1737+	DS USING	OFD *. R5	base for test data and test routine
00002420	00002478	, , , , , , , , , , , , , , , , , , , ,		1738+T30	DC	A(X30)	address of test routine
00002424 00002426	001E 00			1739+ 1740+	DC DC	H' 30' X' 00'	test number
00002420				1741+	DC DC	HL1' 1'	MB used

LOC				RR-a instructi	- 0)		12 Feb 2025 14: 26: 16 Page
1000400	OBJECT CODE	ADDR1	ADDR2	STM			
0002428	01			1742+	DC	HL1' 1'	M5 used
0002429	00			1743+	DC	HL1' 0'	CC
000242A	07			1744+	DC	HL1' 7'	CC failed mask
000242C	0000000 00000000			1745+	DS	2F	extracted PSW after test (has CC)
002434	FF			1746+	DC	X' FF'	extracted CC, if test failed
002435	E5C9E2E3 D9404040			1747+	DC	CL8' VI STR'	instruction name
002440	000024A4			1748+	DC	A(RE30)	address of v1 result
002444	000024B4			1749+	DC	A(RE30+16)	address of v2 source
002448	000024C4			1750+	DC	A(RE30+32)	address of v3 source
00244C	0000010			1751+	DC	A(16)	result length
002450	000024A4			1752+REA30	DC	A(RE30)	result address
002458	0000000 00000000			1753+	DS	FD	
002460	0000000 00000000			1754+V1030	DS	XL16	gap V1 output
	0000000 00000000						1
002470	0000000 0000000			1755+	DS	FD	gap
				1756+*	-		O 1
002478				1757+X30	DS	0F	
002478	4110 8EF8		000010F8	1758+	LA	R1, V1FUDGE	load v21 fudge
00247C	E751 0000 0806		00000000		VL	v21, 0(R1)	
002482	E310 5024 0014		00000024	1760+	ĹĠF	R1, V2ADDR	load v2 source
002488	E761 0000 0806		00000000	1761+	VL	v22, 0(R1)	use v21 to test decoder
00248E	E756 0010 1C5C			1762+		V21, V22, 1, 1	test instruction
002494	B98D 0020			1763+	EPSW	R2, R0	extract psw
002498	5020 500C		000000C		ST	R2, CCPSW	to save CC
00249C	E750 5040 080E		00002460	1765+	VST	V21, V1030	save v1 output
0024A2	07FB		00002100	1766+	BR	R11	return
0024A4	OILD			1767+RE30	DC	0F	V1 for this test
0024A4				1768+	DROP	R5	VI TOI CHIS COSC
	8888888 77777777			1769	DC		7777777 00000000 00000000' v2
	00000000 00000000			1700	ьс	ALIO OCCOOCCO	7777777 00000000 00000000
	8888888 77777777			1770	DC	XI.16' 88888888	7777777 00006666 55555555' v2
	00006666 5555555			1770	DC	ALIO GGGGGGG	7777777 00000000 00000000
				1771			
				1772	VRR_A	VISTR, 1, 1, 0	
0024C8				1773+	DS	OFD	
0024C8		000024C8		1774+	USING	*, R5	base for test data and test routine
0024C8	00002520			1775+T31	DC	A(X31)	address of test routine
0024CC	001F			1776+	DC	H' 31'	test number
0024CE	00			1777+	DC	X' 00'	10.
				1778+	DC	HL1' 1'	MB used
0024D0				1779+	DC	HL1' 1'	M5 used
	0.0			1780+	DC	HL1' 0'	CC
0024D1					Th C		
0024D1 0024D2	07			1781+	DC	HL1' 7'	CC failed mask
0024D1 0024D2 0024D4	07 00000000 00000000			1781+ 1782+	DS	2F	extracted PSW after test (has CC)
0024D1 0024D2 0024D4 0024DC	07 00000000 00000000 FF			1781+ 1782+ 1783+	DS DC	2F X' FF'	extracted PSW after test (has CC) extracted CC, if test failed
0024D1 0024D2 0024D4 0024DC 0024DD	07 00000000 00000000 FF E5C9E2E3 D9404040			1781+ 1782+ 1783+ 1784+	DS DC DC	2F X' FF' CL8' VI STR'	extracted PSW after test (has CC) extracted CC, if test failed instruction name
0024D1 0024D2 0024D4 0024DC 0024DD 0024E8	07 00000000 00000000 FF E5C9E2E3 D9404040 0000254C			1781+ 1782+ 1783+ 1784+ 1785+	DS DC DC DC	2F X' FF' CL8' VI STR' A(RE31)	extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result
0024D1 0024D2 0024D4 0024DC 0024DD 0024E8 0024EC	07 00000000 00000000 FF E5C9E2E3 D9404040 0000254C 0000255C			1781+ 1782+ 1783+ 1784+ 1785+ 1786+	DS DC DC DC	2F X' FF' CL8' VI STR' A(RE31) A(RE31+16)	extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source
0024D1 0024D2 0024D4 0024DC 0024DD 0024E8 0024EC 0024F0	07 00000000 00000000 FF E5C9E2E3 D9404040 0000254C 0000255C 0000256C			1781+ 1782+ 1783+ 1784+ 1785+ 1786+ 1787+	DS DC DC DC DC DC	2F X'FF' CL8' VISTR' A(RE31) A(RE31+16) A(RE31+32)	extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source
0024D1 0024D2 0024D4 0024DC 0024DD 0024E8 0024EC 0024F0 0024F4	07 00000000 00000000 FF E5C9E2E3 D9404040 0000254C 0000255C 0000256C 00000010			1781+ 1782+ 1783+ 1784+ 1785+ 1786+ 1787+ 1788+	DS DC DC DC DC DC DC DC	2F X' FF' CL8' VI STR' A(RE31) A(RE31+16) A(RE31+32) A(16)	extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length
0024D1 0024D2 0024D4 0024DC 0024DD 0024E8 0024EC 0024F0 0024F4 0024F8	07 00000000 00000000 FF E5C9E2E3 D9404040 0000254C 0000255C 00000256C 00000010 0000254C			1781+ 1782+ 1783+ 1784+ 1785+ 1786+ 1787+ 1788+ 1789+REA31	DS DC DC DC DC DC DC DC DC	2F X' FF' CL8' VI STR' A(RE31) A(RE31+16) A(RE31+32) A(16) A(RE31)	extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address
0024D1 0024D2 0024D4 0024DC 0024DD 0024E8 0024EC 0024F0 0024F4 0024F8 002500	07 00000000 00000000 FF E5C9E2E3 D9404040 0000254C 0000256C 00000010 0000254C 0000254C 00000000 00000000			1781+ 1782+ 1783+ 1784+ 1785+ 1786+ 1787+ 1788+ 1789+REA31 1790+	DS DC	2F X' FF' CL8' VI STR' A(RE31) A(RE31+16) A(RE31+32) A(16) A(RE31) FD	extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address
00024D1 00024D2 00024D4 00024DD 00024E8 00024EC 00024F0 00024F4 00024F8 0002500	07 00000000 00000000 FF E5C9E2E3 D9404040 0000254C 0000256C 00000010 0000254C 00000000 00000000 00000000 00000000			1781+ 1782+ 1783+ 1784+ 1785+ 1786+ 1787+ 1788+ 1789+REA31	DS DC DC DC DC DC DC DC DC	2F X' FF' CL8' VI STR' A(RE31) A(RE31+16) A(RE31+32) A(16) A(RE31)	extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length
00024D1 00024D2 00024DC 00024DD 00024E8 00024EC 00024F0 00024F4 00024F8 0002500 0002508	07 00000000 00000000 FF E5C9E2E3 D9404040 0000254C 0000256C 00000010 0000254C 00000000 00000000 00000000 00000000 00000000			1781+ 1782+ 1783+ 1784+ 1785+ 1786+ 1787+ 1788+ 1789+REA31 1790+ 1791+V1031	DS DC	2F X' FF' CL8' VI STR' A(RE31) A(RE31+16) A(RE31+32) A(16) A(RE31) FD XL16	extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output
0024D1 0024D2 0024D4 0024DC 0024DD 0024E8 0024EC 0024F0 0024F4 0024F8 002500 002508	07 00000000 00000000 FF E5C9E2E3 D9404040 0000254C 0000256C 00000010 0000254C 00000000 00000000 00000000 00000000			1781+ 1782+ 1783+ 1784+ 1785+ 1786+ 1787+ 1788+ 1789+REA31 1790+	DS DC	2F X' FF' CL8' VI STR' A(RE31) A(RE31+16) A(RE31+32) A(16) A(RE31) FD	extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address

ASWA Ver.	U. 7. U ZVECTO	or-e/-00-rina (Z)	ector E/ v	kk-a Histructi	OII)		12 re	D 2023 14; 20; 10	rage	40
LOC	OBJECT COL	DE ADDR1	ADDR2	STMI						
00002520				1794+X31	DS	OF				
00002520	4110 8EF8		000010F8	1795+	LA	R1, V1FUDGE	load v21 fudge			
00002524	E751 0000 080)6	00000000	1796+	VL	v21, 0(R1)	roud var rudge			
0000252A	E310 5024 001		00000024	1797+	ĹĠF	R1, V2ADDR	load v2 source			
00002530	E761 0000 080		00000000	1798+	VL	v22, 0(R1)	use v21 to test	decoder		
00002536	E756 0010 1C3			1799+		V21, V22, 1, 1	test ins			
0000253C	B98D 0020			1800+	EPSW	R2, R0	extract psw			
00002540	5020 500C		000000C	1801+	ST	R2, CCPSW	to save CC			
00002544	E750 5040 080)E	00002508	1802+	VST	V21, V1031	save v1 output			
0000254A	07FB			1803+	BR	R11	return			
0000254C				1804+RE31	DC	0F	V1 for this test			
0000254C	00000000 7777	70000		1805+	DROP	R5	77770000 00000000 000	0000019		
0000254C	88888888 7777			1806	DC	YF10, 99999999	77770000 00000000 000	00000' v2		
00002554 0000255C	00000000 0000 8888888 777			1807	DC	VI 16' 9999999	77770000 6666666 555	55555' v2		
00002564	66666666 5555			1007	DC	VIIO 00000000	77770000 00000000 333	JJJJJ V&		
00002304	0000000 3330	,000		1808						
				1809	VRR A	VISTR, 1, 1, 0				
00002570				1810+	DS DS	OFD				
00002570		00002570		1811+	USING		base for test da	ta and test rout:	i ne	
00002570	000025C8			1812+T32	DC	A(X32)	address of test	routi ne		
00002574	0020			1813+	DC	H' 32'	test number			
00002576	00			1814+	DC	X' 00'	_			
00002577	01			1815+	DC	HL1' 1'	MB used			
00002578	01			1816+	DC	肚1'1'	M5 used			
00002579	00			1817+	DC	HL1' 0'	CC Cailed and all			
0000257A	07 00000000 0000	0000		1818+ 1819+	DC DS	HL1' 7' 2F	CC failed mask	ton tost (has CC	`	
0000257C 00002584	FF	J0000		1819+ 1820+	DC DC	X' FF'	extracted PSW af extracted CC, if	ter test (nas to	,	
00002585	E5C9E2E3 D940	04040		1821+	DC	CL8' VI STR'	instruction name			
00002590	000025F4	71010		1822+	DC	A(RE32)	address of v1 re			
00002594	00002611			1823+	DC	A(RE32+16)	address of v2 so			
00002598	00002614			1824+	DC	A(RE32+32)	address of v3 so			
0000259C	0000010			1825+	DC	A(16)	result length			
000025A0				1826+REA32	DC	A(RE32)	result address			
000025A8	00000000 0000			1827+	DS	FD	gap V1 output			
000025B0	00000000 0000			1828+V1032	DS	XL16	V1 output			
000025B8	00000000 0000			1000	D.C.	T'D	<u>.</u>			
000025C0	00000000 0000	0000		1829+	DS	FD	gap			
000025C8				1830+* 1831+X32	DS	OF				
000025C8	4110 8EF8		000010F8	1832+	LA	R1, V1FUDGE	load v21 fudge			
000025CC	E751 0000 080)6	00001018	1833+	VL	v21, 0(R1)	Todu val Tuuge			
000025CC 000025D2	E310 5024 001		00000000	1834+	LGF	R1, V2ADDR	load v2 source			
000025D8	E761 0000 080		00000021	1835+	VL	v22, O(R1)	use v21 to test	decoder		
000025DE	E756 0010 1C			1836+		V21, V22, 1, 1	test ins			
000025E4	B98D 0020			1837+	EPSW	R2, R0	extract psw			
000025E8	5020 500C		000000C	1838+	ST	R2, CCPSW	to save CC			
000025EC	E750 5040 080)E	000025B0	1839+	VST	V21, V1032	save v1 output			
000025F2	07FB			1840+	BR	R11	return			
000025F4				1841+RE32	DC	OF De	V1 for this test			
000025F4	00000000 0000	20000		1842+	DROP	R5	0000000 0000000 000	000001 0		
000025F4	8888888 0000			1843	DC	YF10, 99999888	0000000 00000000 000	00000' v2		
000025FC 00002604	00000000 0000 8888888 0000			1844	DC	YI 16' QQQQQQQ	00007777 66666666 555	55555' v2		
0000260C	66666666 5555			1044	DC	VF10 00000000	00007777 00000000 333	JJJJJ V&		
00002000	00000000 000	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,								

IOC	OD IECT CODE	ADDD 1	A DDD 9	СТМГ			
LOC	OBJECT CODE	ADDR1	ADDR2	STMI			
				1845			
				1846		VISTR, 1, 1, 0	
0002618		00000010		1847+	DS	OFD	
0002618	00000070	00002618		1848+	USING		base for test data and test routine
0002618	00002670			1849+T33	DC	A(X33)	address of test routine
000261C	0021			1850+	DC	H' 33'	test number
000261E	00			1851+	DC	X' 00'	MD wood
000261F 0002620	01 01			1852+ 1853+	DC DC	HL1' 1' HL1' 1'	MB used M5 used
0002621	00			1854+	DC DC	HL1' 0'	CC Wb used
0002622	07			1855+	DC DC	HL1' 7'	CC failed mask
0002624	00000000 00000000			1856+	DS	2F	extracted PSW after test (has CC)
000262C	FF			1857+	DC DC	X' FF'	extracted CC, if test failed
000262D	E5C9E2E3 D9404040			1858+	DC	CL8' VISTR'	instruction name
0002638	0000269C			1859+	DC	A(RE33)	address of v1 result
000263C	000026AC			1860+	DC	A(RE33+16)	address of v2 source
0002640	000026BC			1861+	DC	A(RE33+32)	address of v3 source
0002644	0000010			1862+	DC	A(16)	result length
0002648	0000269C			1863+REA33	DC	A(RE33)	result address
0002650	0000000 00000000			1864+	DS	FD	gap
0002658	00000000 00000000			1865+V1033	DS	XL16	gap V1 output
0002660	00000000 00000000						•
002668	00000000 00000000			1866 +	DS	FD	gap
				1867+*			~ ·
0002670				1868+X33	DS	0F	
0002670	4110 8EF8		000010F8	1869+	LA	R1, V1FUDGE	load v21 fudge
0002674	E751 0000 0806		0000000	1870+	VL_	v21, 0(R1)	
000267A	E310 5024 0014		00000024	1871+	LGF	R1, V2ADDR	load v2 source
0002680	E761 0000 0806		0000000	1872+	VL	v22, 0(R1)	use v21 to test decoder
0002686	E756 0010 1C5C			1873+	VISTR	V21, V22, 1, 1	test instruction
000268C	B98D 0020		0000000	1874+		R2, RO	extract psw
0002690	5020 500C		000000C	1875+	ST	R2, CCPSW	to save CC
002694	E750 5040 080E		00002658	1876+	VST	V21, V1033	save v1 output
00269A	07FB			1877+	BR	R11	return
00269C				1878+RE33	DC	OF D5	V1 for this test
00269C	0000000 0000000			1879+	DROP	R5	0000000 0000000 000000010
00269C	88880000 00000000			1880	DC	XL16, 88880000	00000000 00000000 00000000' v2
0026A4 0026AC	00000000 00000000 88880000 7777777			1881	DC	VI 16! 00000000	7777777 66666666 55555555' v2
0026B4	66666666 55555555			1001	DC	VIIO 99990000	7777777 00000000 33333333 V2
оогода	0000000 3333333			1882			
				1883	VRR A	VI STR, 1, 1, 0	
00026C0				1884+	DS	0FD	
00026C0		000026C0		1885+	USING		base for test data and test routine
00026C0	00002718	00002000		1886+T34	DC	A(X34)	address of test routine
00026C4	0022			1887+	DC	H' 34'	test number
00026C6	00			1888+	DC	X' 00'	
00026C7	01			1889+	DC	HL1' 1'	MB used
00026C8	01			1890+	DC	HL1' 1'	M5 used
00026C9	00			1891+	DC	HL1' 0'	CC
00026CA	07			1892+	DC	HL1' 7'	CC failed mask
00026CC	00000000 00000000			1893+	DS	2F	extracted PSW after test (has CC)
00026D4	FF			1894+	DC	X' FF'	extracted CC, if test failed
00026D5	E5C9E2E3 D9404040			1895+	DC	CL8' VISTR'	instruction name
00026E0	00002744			1896+	DC	A(RE34)	address of v1 result
00026E4	00002754			1897+	DC	A(RE34+16)	address of v2 source

SMH VEI.	0. 7. 0 Zvector- e7- 00	o-rina (Zv	ector E7 v	MN-a HISCHUCE	i Oii)		12 Feb 2023 14	1. 20. 10	rage	44
LOC	OBJECT CODE	ADDR1	ADDR2	STM						
00026E8	00002764			1898+	DC	A(RE34+32)	address of v3 source			
00026EC	0000010			1899+	DC	A(16)	result length			
00026F0	00002744			1900+REA34	DC	A(RE34)	result address			
00026F8	0000000 00000000			1901+	DS	FD	gap V1 output			
0002700	0000000 00000000			1902+V1034	DS	XL16	V1 output			
0002708	0000000 00000000									
0002710	0000000 00000000			1903+	DS	FD	gap			
.0000710				1904+*	D.C.	0.				
0002718	4440 OFFO		00001000	1905+X34	DS	OF	1 1 01 6 1			
0002718	4110 8EF8		000010F8	1906+	LA	R1, V1FUDGE	load v21 fudge			
000271C	E751 0000 0806		00000000	1907+	VL	v21, 0(R1)	1 1 0			
0002722 0002728	E310 5024 0014 E761 0000 0806		00000024 00000000	1908+	LGF VL	R1, V2ADDR	load v2 source			
0002728	E756 0010 1C5C		0000000	1909+ 1910+		v22, 0(R1) V21, V22, 1, 1	use v21 to test decoder test instruction			
0002721	B98D 0020			1910+	EPSW	R2, R0	extract psw			
0002734	5020 500C		000000C	1912+	ST	R2, CCPSW	to save CC			
000273C	E750 5040 080E		00002700	1913+	VST	V21, V1034	save v1 output			
0002742	07FB		00002700	1914+	BR	R11	return			
0002744	0.11			1915+RE34	DC	0F	V1 for this test			
0002744				1916+	DROP	R5				
0002744	0000000 00000000			1917	DC	XL16' 00000000	0000000 00000000 00000000'	$\mathbf{v2}$		
000274C	0000000 00000000									
0002754	00008888 77777777			1918	DC	XL16' 00008888	7777777 6666666 55555555'	v2		
000275C	66666666 55555555									

VISTR V21, V22, 2, 1

R2, CCPSW

EPSW R2, R0

test instruction

extract psw

to save CC

2022+

2023+

2024+

000000C

E756 0010 2C5C

B98D 0020

5020 500C

00002926

0000292C

DC

HL1'2'

MB used

2075 +

00002A0F

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002A10	01			2076+	DC	HL1' 1'	M5 used
00002A11				2077+	DC	HL1' 0'	CC
00002A12	07			2078+	DC	HL1' 7'	CC failed mask
00002A14	00000000 00000000			2079+	DS	2F	extracted PSW after test (has CC)
00002A1C	FF			2080+	DC	X' FF'	extracted CC, if test failed
00002A1D	E5C9E2E3 D9404040			2081+	DC	CL8' VI STR'	instruction name
00002A28	00002A8C			2082+	DC	A(RE39)	address of v1 result
00002A2C	00002A9C			2083+	DC	A(RE39+16)	address of v2 source
00002A30	00002AAC			2084+	DC	A(RE39+32)	address of v3 source
00002A34	00000010			2085+	DC	A(16)	result length
00002A38	00002A8C			2086+REA39	DC	A(RE39)	result address
00002A40	00000000 00000000			2087+	DS	FD	gap V1 output
00002A48	00000000 00000000			2088+V1039	DS	XL16	vi output
00002A50	00000000 00000000			9090.	DC	ED	
00002A58	00000000 00000000			2089+ 2090+*	DS	FD	gap
00002A60				2091+X39	DS	0F	
00002A60	4110 8EF8		000010F8	2092+	LA	R1, V1FUDGE	load v21 fudge
00002A64	E751 0000 0806		00000000	2093+	VL	v21, 0(R1)	
00002A6A	E310 5024 0014		00000024	2094+	LGF	R1, V2ADDR	load v2 source
00002A70	E761 0000 0806		00000000	2095+	VL	v22, 0(R1)	use v21 to test decoder
00002A76	E756 0010 2C5C			2096+	VISTR	V21, V22, 2, 1	test instruction
00002A7C	B98D 0020			2097+	EPSW	R2, R0	extract psw
00002A80	5020 500C		000000C	2098+	ST	R2, CCPSW	to save CC
00002A84	E750 5040 080E		00002A48	2099+	VST	V21, V1039	save v1 output
00002A8A	07FB			2100+	BR	R11	return
00002A8C				2101+RE39	DC	0F	V1 for this test
00002A8C	0000000 0000000			2102+	DROP	R5	0.0000000 0000000 00000001
00002A8C	00000000 00000000			2103	DC	XL16, 00000000	0 00000000 00000000 00000000' v2
00002A94	00000000 00000000			0104	D.C.	VI 101 00000000	D DDDDDDD CCCCCCC DDDDDDDD0
00002A9C 00002AA4	OOOOOOO BBBBBBBB CCCCCCC DDDDDDDD			2104	DC	YF10, 00000000	O BBBBBBB CCCCCCC DDDDDDDDD' v2
				2105			
				2106			
00000115				2107	D .C	TI 01	OF TARY
00002AAC	00000000			2108	DC		OF TABLE
00002AB0	0000000			2109	DC	F' 0'	

DC

DC

DC

A(0)

F' 0'

F' 0'

END OF TABLE

end of table

2158+

2159

2160

2161

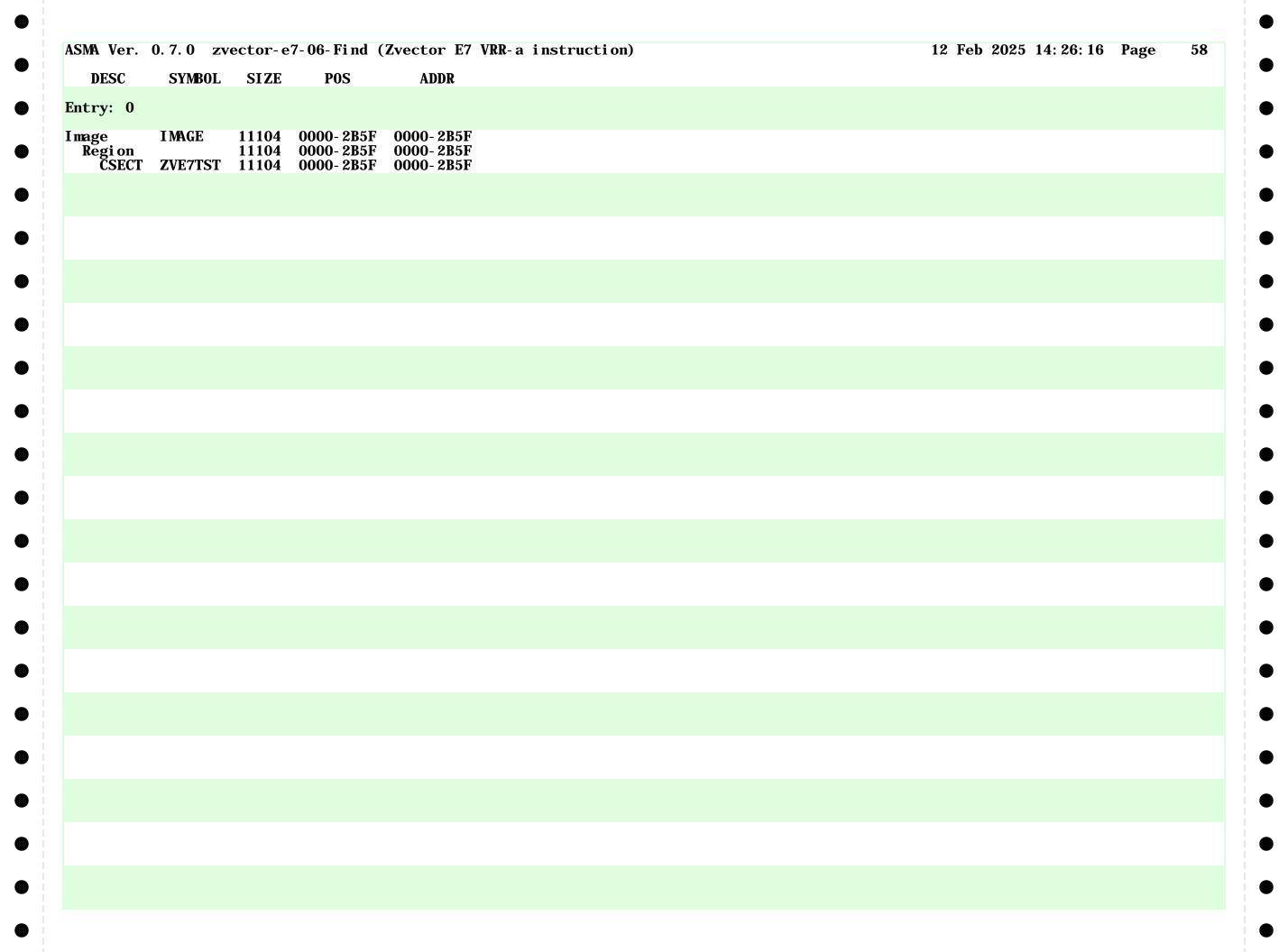
00002B54

00002B58 00000000

00002B5C 00000000

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFER	ENCES											
EGI N	I	00000200	2	151	117	147	148	149									
C	Ū	00000000	~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~	512	262		110	110									
CFOUND	X	00000014	1	518	249	269											
CMASK	Ü	000000A	$\bar{1}$	513	219												
CMSG	Ū	0000031C	$\bar{1}$	236	231												
CPRTEXP	Č	00001098	1	477	266												
CPRTGOT	C	000010A8	1	480	273												
CPRTLI NE	C	00001055	16	472	482	276											
CPRTLNG	U	00000055	1	482	275												
CPRTNAME	C	00001082	8	475	259												
CPRTNUM	C	00001065	3	473	257												
CPSW	F	000000C	4	517	246	684	721	758	796	833	870	908	945	982	1023	1060	1097
					1134	1171	1208	1245	1282	1319	1356	1393	1430	1467	1504	1541	1578
					1616	1653	1690	1727	1764	1801	1838	1875	1912	1950	1987	2024	2061
	_				2098												
TLRO	F	00000554	4	415	161	162	163	164									
ECNUM	C	000010D6	16	492	254	256	263	265	270	272	292	294	301	303	308	310	
7TEST	4	00000000	88	506	210												
7TESTS	F	00002AB4	4	2114	203	004	0~4	000	000	000							
DIT	X	000010AA	18	487	255	264	271	293	302	309							
NDTEST	U	00000428	1	330	208	000											
0J	Ţ	00000538	4	405	196	333											
OJPSW	D	00000528	8	403	405												
ALLED	U	00000418	1	320	000	000	001										
ALLED	F	00001000	4	445	280	322	331										
ALLDSW	U	000003B0	1	290	226												
AILPSW AILTEST	D	00000540 00000550	8	407	409												
B0001	T T	00000330	4 8	409 180	334	185	187										
MAGE	г 1	00000280	11104	0	184	100	10/										
WAGE	II	0000000	11104	429	430	431	432										
64	Ü	00010000	1	429	430	431	432										
B	Ü	00010007	1	510	300												
5	Ü	0000007	1	511	240	307											
B	II	00100000	1	432	240	307											
SG	T	00000470	4	365	195	348											
SGCMD	Ċ	00000470 000004BE	9	395	378	3 7 9											
SGMSG	Č	000004BE	95	396	378 372	393	370										
SGMVC	Ĭ	000004E7	6	393	376	300	3.0										
SGOK	Ī	000004B6	2	374	370 371												
SGRET .	Ī	00000100 000004A6	$\tilde{4}$	389	382	385											
BGSAVE	F	000004AC	4	392	368	389											
EXTE7	Ū	000002D4	Î.	205	229	325											
PNAME	č	00000015	8	520	259	297											
AGE	Ü	00001000	1	430													
RT3	C	000010C0	18	490	255	256	257	264	265	266	271	272	273	293	294	295	302
	~	00001055			303	304	309	310	311								
RTLI NE	C	00001008	16	454	464	314											
RTLNG	U	0000004D	1	464	313												
RTMB	C	00001044	3	459	304												
RTM5	Ü	00001051	3	462	311												
RTNAME	C	00001033	8	457	297 205												
RTNUM	C U	00001018 00000000	3	455 2167	295 111	101	104	184	100	187	188	193	212	213	275	279	280
				7167		161	164	1 X 4	186	IX'/	IXX	143	717	ソース	7/5	774	7X()
0	U	0000000	4	2107	313	321	322	347	349	365	368	370	372	374	389	683	720

) zvect REFEREN												12 Feb				
CHECK FTABLE	63 611	170 2115																
RR_A	546	655	692 1327 1958	729 1364 1995	767 1401 2032	804 1438 2069	841 1475	879 1512	916 1549	953 1587	994 1624	1031 1661	1068 1698	1105 1735	1142 1772	1179 1809	1216 1846	1253 1883



ASMA Ver. 0.7.0 zvector-e7-06-Find (Zvector E7 VRR-a instruction)	12 Feb 2025 14: 26: 16 Page 59
STMI FILE NAME	
1 /home/tn529/sharedvfp/tests/zvector-e7-08-VISTR. asm	
** NO ERRORS FOUND **	
NO ERRORS FOUND	